

RL78/G1A

RENESAS MCU

R01DS0151EJ0210 Rev.2.10 Nov 30, 2016

Combines Multi-channel 12-Bit A/D Converter, True Low Power Platform (as low as 66 μ A/MHz, and 0.57 μ A for RTC + LVD), 1.6 V to 3.6 V operation, 16 to 64 Kbyte Flash, 41 DMIPS at 32 MHz

1. OUTLINE

1.1 Features

Ultra-Low Power Technology

- 1.6 V to 3.6 V operation from a single supply
- Stop (RAM retained): 0.23 μA, (LVD enabled): 0.31 μA
- Halt (RTC + LVD): 0.57 μA
- Snooze: 0.7 mA (UART), 0.6 mA (ADC)
- Operating: 66 μA/MHz

16-bit RL78 CPU Core

- Delivers 41 DMIPS at maximum operating frequency of 32 MHz
- Instruction Execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

Code Flash Memory

- Density: 16 KB to 64 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with secure boot swap function and flash shield window function

Data Flash Memory

- Data Flash with background operation
- Data flash size: 4 KB
- Erase Cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 3.6 V

RAM

- 2 KB to 4 KB size options
- Supports operands or instructions
- Back-up retention in all modes

High-speed On-chip Oscillator

- 32 MHz with +/- 1% accuracy over voltage (1.8 V to 3.6 V) and temperature (-20 °C to +85 °C)
- Pre-configured settings: 32 MHz, 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz, and 1 MHz

Reset and Supply Management

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 12 setting options (Interrupt and/or reset function)

Data Memory Access (DMA) Controller

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

Multiple Communication Interfaces

- Up to 6 x I2C master
- Up to 1 x I²C multi-master
- Up to 6 x CSI/SPI (7-, 8-bit)
- Up to 3 x UART (7-, 8-, 9-bit)
- Up to 1 x LIN

Extended-Function Timers

- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

Rich Analog

- ADC: Up to 28 channels, 12-bit resolution, 3.375 μs conversion time
- Supports 1.6 V
- Internal voltage reference (1.45 V)
- On-chip temperature sensor

Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- RAM parity error check
- RAM write protection
- SFR write protection
- Illegal memory access detection
- Clock stop/ frequency detection
- ADC self-test

General Purpose I/O

- 3.6 V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

Operating Ambient Temperature

- Standard: -40 °C to +85 °C
- Extended: -40 °C to +105 °C

Package Type and Pin Count

From 3 mm x 3 mm to 10 mm x 10 mm

QFP: 48, 64 QFN: 32, 48 LGA: 25 BGA: 64

O ROM, RAM capacities

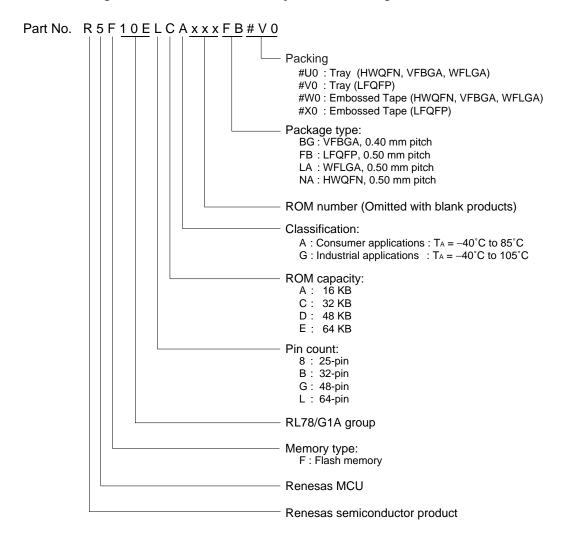
Flash ROM	Data flash	RAM	RL78/G1A					
			25 pins	25 pins 32 pins 48 pins		64 pins		
64 KB	4 KB 4 KB Note		R5F10E8E	R5F10EBE	R5F10EGE	R5F10ELE		
48 KB	4 KB	3 KB	R5F10E8D	R5F10EBD	R5F10EGD	R5F10ELD		
32 KB	2 KB 4 KB 2 KB		R5F10E8C	8C R5F10EBC R5F10EGC		R5F10ELC		
16 KB	4 KB	2 KB	R5F10E8A	R5F10EBA	R5F10EGA	_		

Note This is about 3 KB when the self-programming function and data flash function are used. (For details, see

3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS TA = -40 to +105°C))

1.2 List of Part Numbers

Figure 1-1. Part Number, Memory Size, and Package of RL78/G1A



Caution The part number above is valid as of when this manual was issued. For the latest part number, see the web page of the target product on the Renesas Electronics website.

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Table 1-1. List of Ordering Part Numbers

Pin count	Package	Fields of Application ^{Note}	Ordering Part Number
25 pins	25-pin plastic WFLGA (3 × 3 mm, 0.5 mm pitch)	А	R5F10E8AALA#U0, R5F10E8CALA#U0, R5F10E8DALA#U0, R5F10E8EALA#U0, R5F10E8AALA#W0, R5F10E8CALA#W0, R5F10E8DALA#W0, R5F10E8EALA#W0
		G	R5F10E8AGLA#U0, R5F10E8CGLA#U0, R5F10E8DGLA#U0, R5F10E8EGLA#U0, R5F10E8AGLA#W0, R5F10E8CGLA#W0, R5F10E8DGLA#W0, R5F10E8EGLA#W0
32 pins	32-pin plastic HWQFN (5 × 5 mm, 0.5 mm pitch)	А	R5F10EBAANA#U0, R5F10EBCANA#U0, R5F10EBDANA#U0, R5F10EBEANA#U0, R5F10EBAANA#W0, R5F10EBCANA#W0, R5F10EBDANA#W0, R5F10EBEANA#W0
		G	R5F10EBAGNA#U0, R5F10EBCGNA#U0, R5F10EBDGNA#U0, R5F10EBEGNA#U0, R5F10EBAGNA#W0, R5F10EBCGNA#W0, R5F10EBDGNA#W0, R5F10EBEGNA#W0
48 pins	48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)	А	R5F10EGAAFB#V0, R5F10EGCAFB#V0, R5F10EGDAFB#V0, R5F10EGEAFB#V0, R5F10EGAAFB#X0, R5F10EGCAFB#X0, R5F10EGDAFB#X0, R5F10EGEAFB#X0
		G	R5F10EBAGNA#V0, R5F10EBCGNA#V0, R5F10EBDGNA#V0, R5F10EBEGNA#V0, R5F10EBAGNA#X0, R5F10EBCGNA#X0, R5F10EBDGNA#X0, R5F10EBEGNA#X0
	48-pin plastic HWQFN (7 × 7 mm, 0.5 mm pitch)	A	R5F10EGAANA#U0, R5F10EGCANA#U0, R5F10EGDANA#U0, R5F10EGEANA#U0, R5F10EGAANA#W0, R5F10EGCANA#W0, R5F10EGDANA#W0, R5F10EGEANA#W0
		G	R5F10EGAGNA#U0, R5F10EGCGNA#U0, R5F10EGDGNA#U0, R5F10EGEGNA#U0, R5F10EGAGNA#W0, R5F10EGCGNA#W0, R5F10EGDGNA#W0, R5F10EGEGNA#W0
64 pins	64-pin plastic LFQFP (10 × 10 mm, 0.5 mm	А	R5F10ELCAFB#V0, R5F10ELDAFB#V0, R5F10ELEAFB#V0, R5F10ELCAFB#X0, R5F10ELDAFB#X0, R5F10ELEAFB#X0
	pitch)	G	R5F10ELCGFB#V0, R5F10ELDGFB#V0, R5F10ELEGFB#V0, R5F10ELCGFB#X0, R5F10ELDGFB#X0, R5F10ELEGFB#X0
	64-pin plastic VFBGA (4 × 4 mm, 0.4 mm pitch)	А	R5F10ELCABG#U0, R5F10ELDABG#U0, R5F10ELEABG#U0, R5F10ELCABG#W0, R5F10ELDABG#W0, R5F10ELEABG#W0
		G	R5F10ELCGBG#U0, R5F10ELDGBG#U0, R5F10ELEGBG#U0, R5F10ELCGBG#W0, R5F10ELDGBG#W0, R5F10ELEGBG#W0

<R> Note For the fields of application, see Figure 1-1 Part Number, Memory Size, and Package of RL78/G1A.

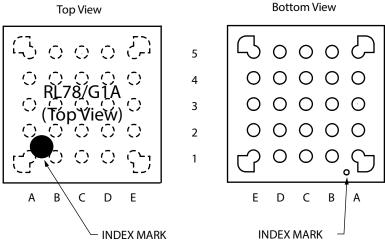
Caution The part number above is valid as of when this manual was issued. For the latest part number, see the web page of the target product on the Renesas Electronics website.

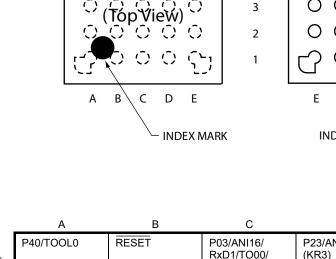
1.3 Pin Configuration (Top View)

1.3.1 25-pin products

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• 25-pin plastic WFLGA (3 × 3 mm, 0.50 mm pitch)





	Α	В	С	D	E	
5	P40/TOOL0	RESET	P03/ANI16/ RxD1/TO00/ (KR1)	P23/ANI3/ (KR3)	AVss	5
4	P122/X2/ EXCLK	P137/INTP0	P02/ANI17/ TxD1/TI00/ (KR0)	P22/ANI2/ (KR2)	AV _{DD}	4
3	P121/X1	V _{DD}	P21/ANI1/ AVREFM	P11/ANI20/ SI00/SDA00/ RxD0/ TOOLRxD	P10/ANI18/ SCK00/SCL00	3
2	REGC	Vss	P30/ANI27/ SCK11/SCL11/ INTP3	P51/ANI25/ SO11/INTP2	P50/ANI26/ SI11/SDA11 INTP1	2
1	P60/SCLA0	P61/SDAA0	P31/ANI29/TI03/ TO03/PCLBUZ0 /INTP4	P12/ANI21/ SO00/TxD0/ TOOLTxD	P20/ANI0/ AV _{REFP}	1
	A	В	С	D	Е	•

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

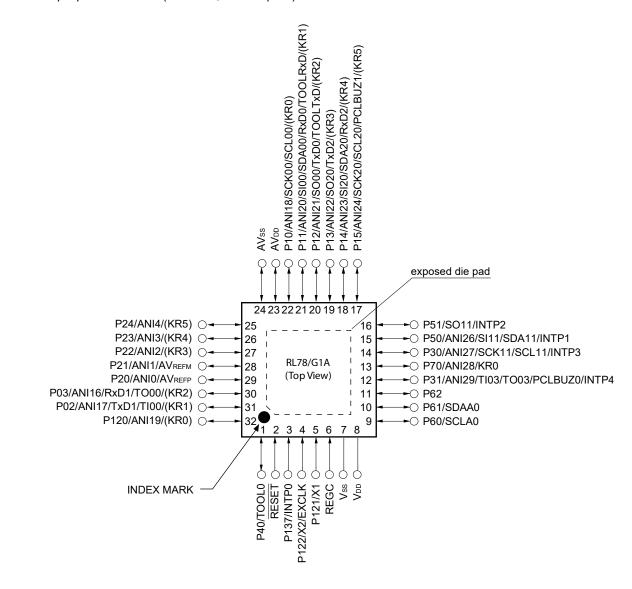
RL78/G1A **OUTLINE**

1.3.2 32-pin products

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• 32-pin plastic HWQFN (5 × 5 mm, 0.5 mm pitch)



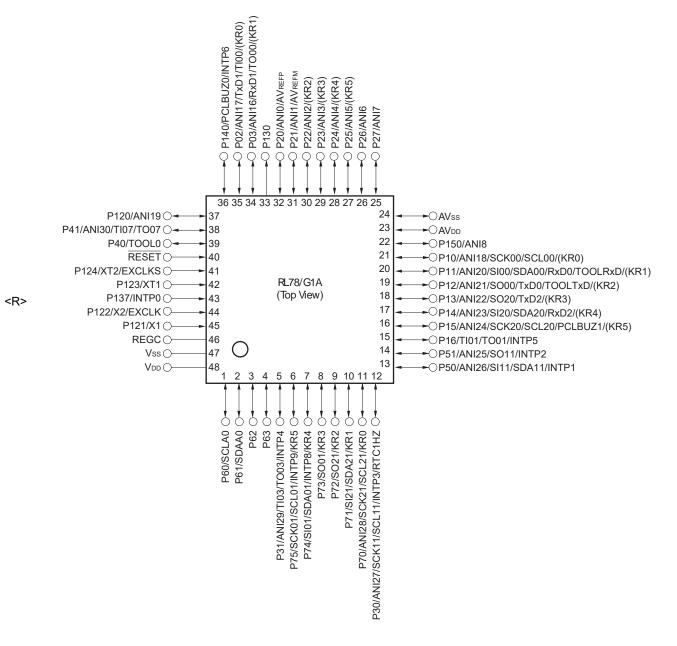
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

- 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).
- 3. It is recommended to connect an exposed die pad to $V_{\mbox{\scriptsize ss}}$.

1.3.3 48-pin products

• 48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)

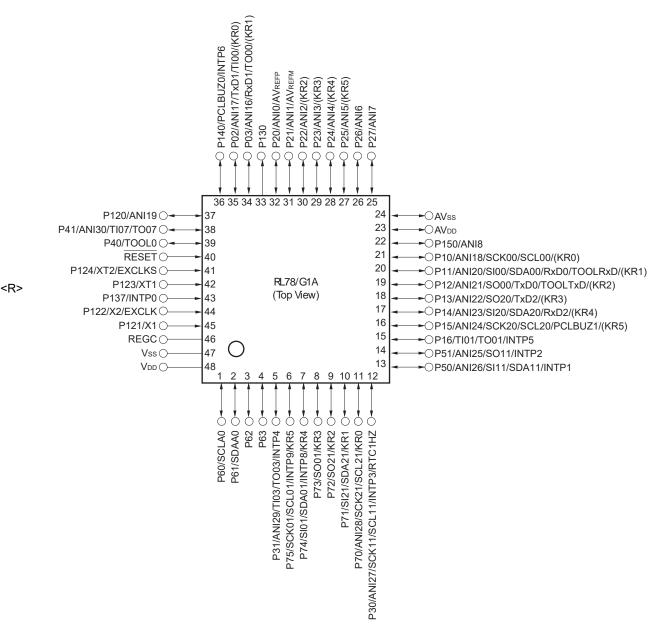


Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

• 48-pin plastic HWQFN (7 × 7 mm, 0.5 mm pitch)



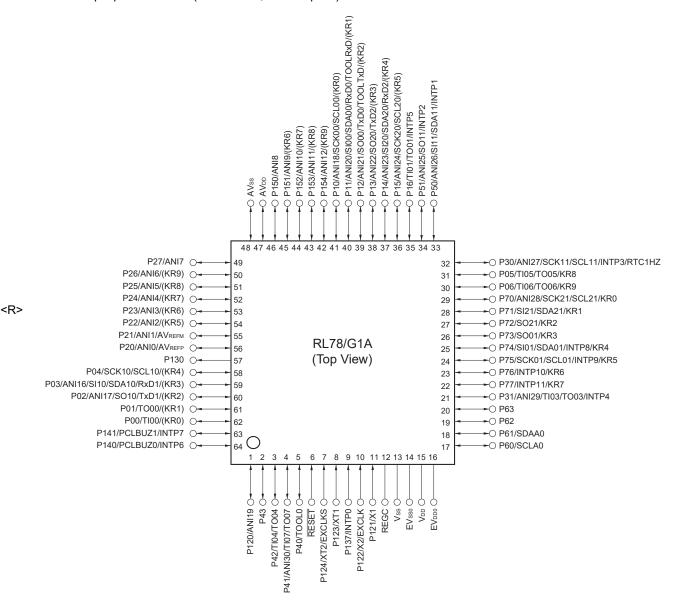
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.3.4 64-pin products

• 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)



Cautions 1. Make EVsso pin the same potential as Vss pin.

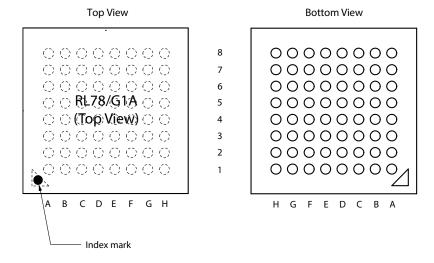
- 2. Make VDD pin the potential that is higher than EVDDO pin.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see **1.4 Pin Identification**.

- 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD0} pins and connect the Vss and EVss0pins to separate ground lines.
- **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

• 64-pin plastic VFBGA (4 × 4 mm, 0.4 mm pitch)

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Pin No.	Name	Pin No.	Name	Pin No.	Name	Pin No.	Name
A1	P05/TI05/TO05/KR8	C1	P51/ANI25/SO11 /INTP2	E1	P153/ANI11/(KR8)	G1	AVDD
A2	P30/ANI27/SCK11 /SCL11/INTP3 /RTC1HZ	C2	P71/SI21/SDA21/KR1	E2	P154/ANI12/(KR9)	G2	P25/ANI5/(KR8)
A3	P70/ANI28/SCK21 /SCL21/KR0	C3	P74/SI01/SDA01 /INTP8/KR4	E3	P10/ANI18/SCK00 /SCL00/(KR0)	G3	P24/ANI4/(KR7)
A4	P75/SCK01/SCL01 /INTP9/KR5	C4	P16/TI01/TO01/INTP5	E4	P11/ANI20/SI00 /SDA00/RxD0 /TOOLRxD/(KR1)	G4	P22/ANI2/(KR5)
A5	P77/INTP11/KR7	C5	P15/ANI24/SCK20 /SCL20/(KR5)	E5	P03/ANI16/SI10 /SDA10/RxD1/(KR3)	G5	P130
A6	P61/SDAA0	C6	P63	E6	P41/ANI30/TI07/TO07	G6	P02/ANI17/SO10/TxD1 /(KR2)
A7	P60/SCLA0	C7	Vss	E7	RESET	G7	P00/TI00/(KR0)
A8	EV _{DD0}	C8	P121/X1	E8	P137/INTP0	G8	P124/XT2/EXCLKS
B1	P50/ANI26 /SI11 /SDA11/INTP1	D1	P13/ANI22/SO20 /TxD2/(KR3)	F1	P150/ANI8	H1	AVss
B2	P72/SO21/KR2	D2	P06/TI06/TO06/KR9	F2	P151/ANI9/(KR6)	H2	P27/ANI7
ВЗ	P73/SO01/KR3	D3	P12/ANI21/SO00 /TxD0/TOOLTxD/(KR2)	F3	P152/ANI10/(KR7)	H3	P26/ANI6/(KR9)
B4	P76/INTP10/KR6	D4	P14/ANI23/SI20/ SDA20/RxD2/(KR4)	F4	P21/ANI1/AVREFM	H4	P23/ANI3/(KR6)
B5	P31/ANI29/TI03/TO03 /INTP4	D5	P42/TI04/TO04	F5	P04/SCK10/SCL10 /(KR4)	H5	P20/ANI0/AVREFP
B6	P62	D6	P40/TOOL0	F6	P43	H6	P141/PCLBUZ1/INTP7
B7	V _{DD}	D7	REGC	F7	P01/TO00/(KR1)	H7	P140/PCLBUZ0/INTP6
B8	EVsso	D8	P122/X2/EXCLK	F8	P123/XT1	H8	P120/ANI19

- Cautions 1. Make EVsso pin the same potential as Vss pin.
 - 2. Make V_{DD} pin the potential that is higher than EV_{DD0} pin.
 - 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).
- Remarks 1. For pin identification, see 1.4 Pin Identification.
 - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD0} pins and connect the Vss and EV_{SS0} pins to separate ground lines.
 - **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



1.4 Pin Identification

ANI0 to ANI12, PCLBUZ0, PCLBUZ1: Programmable clock output/buzzer

ANI16 to ANI30: Analog input output

AV_{DD}: Analog power supply REGC: Regulator capacitance

AVss: Analog ground RESET: Reset

AVREFM: A/D converter reference RTC1HZ: Real-time clock correction clock

potential (– side) input (1 Hz) output

AV_{REFP}: A/D converter reference RxD0 to RxD2: Receive data

potential (+ side) input SCK00, SCK01, SCK10,

EVDDO: Power supply for port SCK11, SCK20, SCK21: Serial clock input/output

EVsso: Ground for port SCLA0, SCL00, SCL01, EXCLK: External clock input (main SCL10, SCL11, SCL20,

system clock) SCL21: Serial clock output

EXCLKS: External clock input SDAA0, SDA00, SDA01,

(subsystem clock) SDA10, SDA11, SDA20,

INTP0 to INTP11: Interrupt Request from SDA21: Serial data input/output

External SI00, SI01, SI10, SI11,

KR0 to KR9: Key return SI20, SI21: Serial data input

P00 to P06: Port 0 S000, S001, S010,

P10 to P16: Port 1 SO11, SO20, SO21: Serial data output

P20 to P27: Port 2 TI00, TI01, TI03 to TI07: Timer input

P30, P31: Port 3 TO00, TO01,

P40 to P43: Port 4 TO03 to TO07: Timer output

P50, P51: Port 5 TOOL0: Data input/output for tool

P60 to P63: Port 6 TOOLRxD, TOOLTxD: Data input/output for external device

 P70 to P77:
 Port 7
 TxD0 to TxD2:
 Transmit data

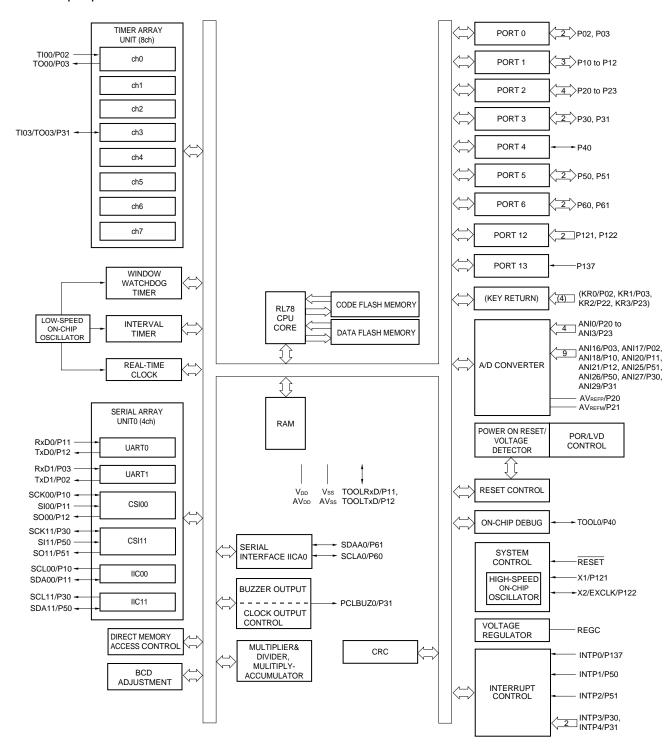
 P120 to P124:
 Port 12
 V_{DD}:
 Power supply

 P130, P137:
 Port 13
 Vss:
 Ground

P140, P141: Port 14 X1, X2: Crystal oscillator (main system clock)
P150 to P154: Port 15 XT1, XT2: Crystal oscillator (subsystem clock)

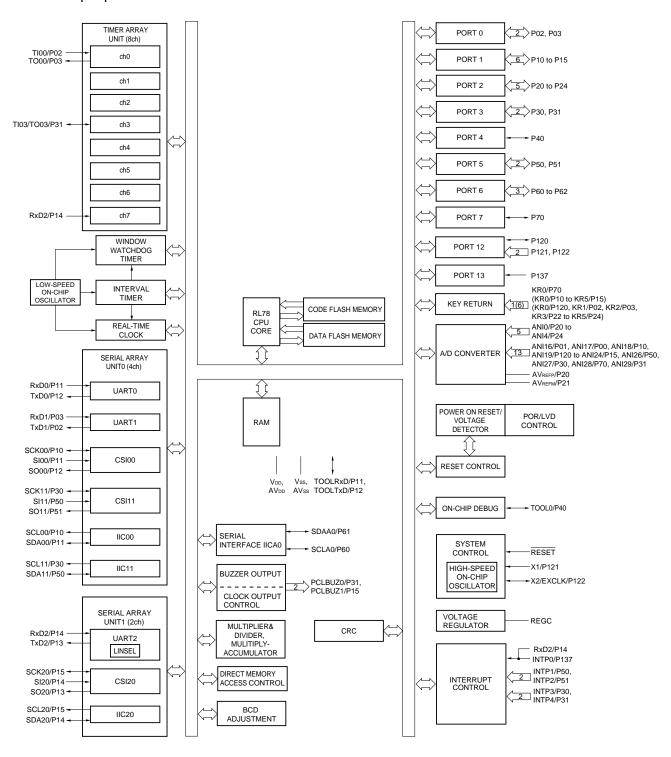
1.5 Block Diagram

1.5.1 25-pin products



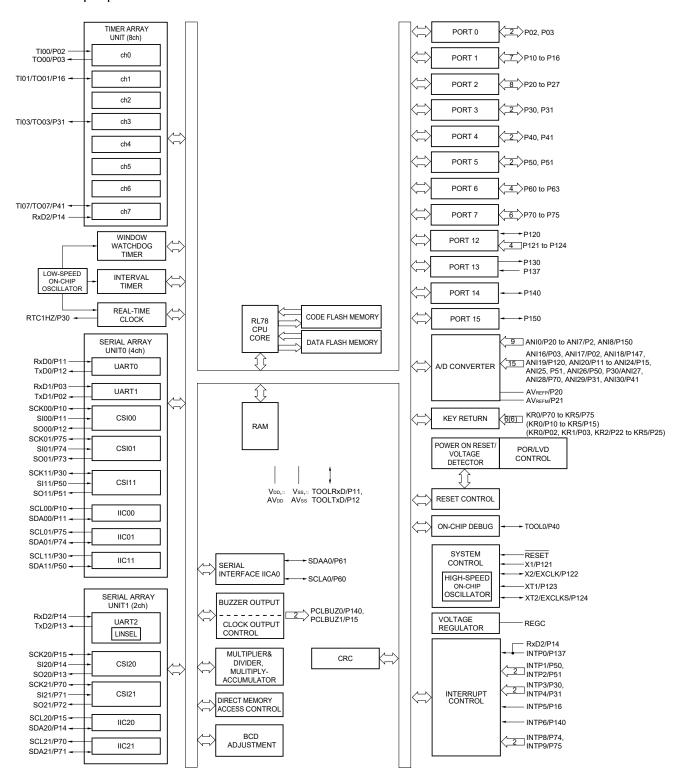
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

<R> 1.5.2 32-pin products



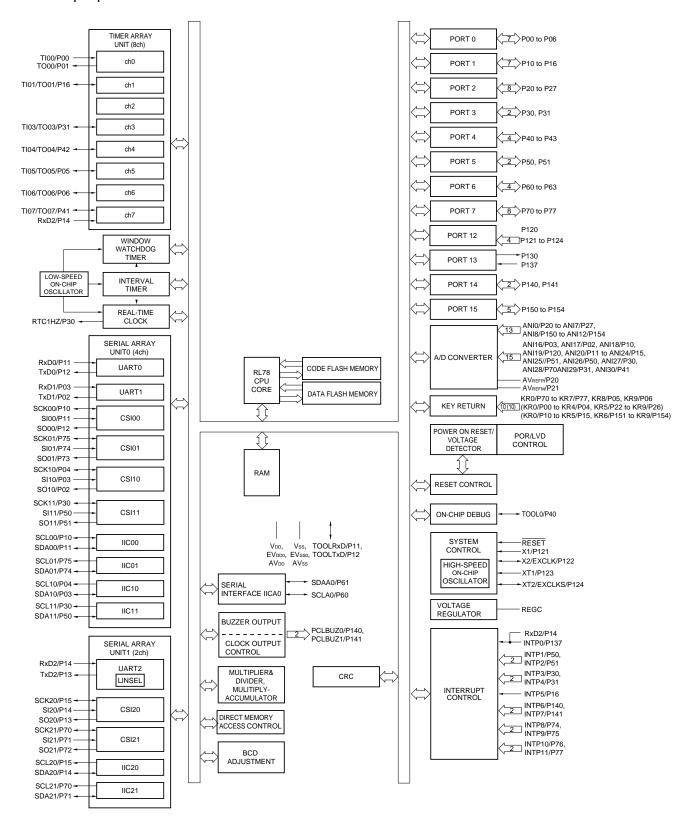
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

<R> 1.5.3 48-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.4 64-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.6 Outline of Functions

(1/2)

	RTC output		_	1 Hz (subsystem close)	ck: fsuв = 32.768 kHz)		
	Timer output	2 channels (PWM output	s: 1 ^{Note 3})	4 channels (PWM outputs: 3 Note 3)	7 channels (PWM outputs: 6 Note 3)		
	12-bit interval timer (IT)		1 cha	annel			
Watchdog timer Real-time clock (RTC)		1 chan	nel ^{Note 2}	1 cha	annel		
			1 cha	annel			
Timer	16-bit timer		8 cha	nnels			
	N-ch open-drain I/O (6 V tolerance)	2	3	4	4		
	CMOS output	_		1	1		
	CMOS input	3	3	5	5		
	CMOS I/O	14 (N-ch O.D. I/O [V _{DD} withstand voltage]: 6)	20 (N-ch O.D. I/O [V _{DD} withstand voltage]: 9)	32 (N-ch O.D. I/O [V _{DD} withstand voltage]: 11)	46 (N-ch O.D. I/O [V _{DD} withstand voltage]: 12		
I/O port	Total	19	26	42	56		
Instruction se	t	 Data transfer (8/16 bits) Adder and subtractor/logical operation (8/16 bits) Multiplication (8 bits × 8 bits) Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc. 					
		$-$ 30.5 μ s (Subsystem clock: fsuB = 32.768 kHz operation)					
		, , , , , , ,	stem clock: f _{MX} = 20 MHz				
<u> </u>	ruction execution time	, ,	on-chip oscillator: f _{IH} = 3	2 MHz operation)			
General-purp	•	(8-bit register × 8) × 4 bank					
Low-speed or	n-chip oscillator	15 kHz (TYP.)		CIOCK IIIPUL (EAGENS)	32.700 KHZ (11F.)		
Subsystem cl	ock		_	XT1 (crystal) oscillation, clock input (EXCLKS)	-		
		LV (Low-voltage main) r	node : 1 to 4 MHz (V _{DD}				
		LS (Low-speed main) m	,	•			
	oscillator		node : 1 to 16 MHz (Vo	•			
	High-speed on-chip	, , ,	node : 1 to 32 MHz (Vo	,			
Main system clock	High-speed system clock	X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) HS (High-speed main) mode: 1 to 20 MHz (V _{DD} = 2.7 to 3.6 V), HS (High-speed main) mode: 1 to 16 MHz (V _{DD} = 2.4 to 3.6 V), LS (Low-speed main) mode: 1 to 8 MHz (V _{DD} = 1.8 to 3.6 V), LV (Low-voltage main) mode: 1 to 4 MHz (V _{DD} = 1.6 to 3.6 V)					
Address space	e	1 MB					
RAM (KB)		2 to 4 Note 1	2 to 4 Note 1	2 to 4 Note 1	2 to 4 Note 1		
Data flash me	emory (KB)	4	4	4	4		
Code flash m	emory (KB)	16 to 64	16 to 64	16 to 64	32 to 64		
		R5F10E8x	R5F10EBx	R5F10EGx	R5F10ELx		
	Item	25-pin	32-pin	48-pin	64-pin		

Notes 1. In the case of the 4 KB, this is about 3 KB when the self-programming function and data flash function are used. (For details, see CHAPTER 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS TA = -40 to +105°C))

- 2. Only the constant-period interrupt function when the low-speed on-chip oscillator clock (fill) is selected
- The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves). (6.9.3 Operation as multiple PWM output function).



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(2/2)

					(2/2)		
Ite	m	25-pin	32-pin	48-pin	64-pin		
		R5F10E8x	R5F10EBx	R5F10EGx	R5F10ELx		
Clock output/buzz	er output	1 • 2.44 kHz, 4.88 kHz, 9.7 2.5 MHz, 5 MHz, 10 M (Main system clock: fw		• 256 Hz, 512 Hz, 1.024 4.096 kHz, 8.192 kHz,	Hz aın = 20 MHz operation)		
8/12-bit resolution	A/D converter	13 channels	18 channels	24 channels	28 channels		
Serial interface		[25-pin products]	1 12 211211111212				
		 CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel [32-pin products] CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART (UART supporting LIN-bus): 1 channel [48-pin products] CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART (UART supporting LIN-bus): 1 channel [64-pin products] CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel 					
	I ² C bus	1 channel	olified I ² C: 2 channels/UA 1 channel	1 channel	1 channel		
Multiplier and divider/multiply-ac	cumulator	• 32 bits ÷ 32 bits = 32 b	Dits (Unsigned or signed) Dits (Unsigned) Dits (Unsigned) Dits = 32 bits (Unsigned o	r signed)			
DMA controller		2 channels					
Vectored interrupt	Internal	24	27	27	27		
sources	External	6	6	10	13		
Key interrupt		0 ch (4 ch) ^{Note 1}	1 ch (6 ch) ^{Note 1}	6 ch	10 ch		
Reset		 Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution^{Note 2} Internal reset by RAM parity error Internal reset by illegal-memory access 					
Power-on-reset ci	rcuit	Power-on-reset: 1.8 Power-down-reset: 1.8	51 V (TYP.) 50 V (TYP.)				
Voltage detector			.67 V to 3.14 V (12 stage .63 V to 3.06 V (12 stage				
On-chip debug fur	nction	Provided					
Power supply volta	age	V _{DD} = 1.6 to 3.6 V					
Operating ambien	t temperature	$T_A = -40 \text{ to } +85^{\circ}\text{C } (A: C)$	onsumer application), Ta	= -40 to +105°C (G: Indu	strial application)		

Notes 1. Can be used by the Peripheral I/O redirection register (PIOR).

2. The illegal instruction is generated when instruction code FFH is executed.
Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

2. ELECTRICAL SPECIFICATIONS $(T_A = -40 \text{ to } +85^{\circ}\text{C})$

This chapter describes the following electrical specifications.

Target products A: Consumer applications $TA = -40 \text{ to } +85^{\circ}\text{C}$

R5F10E8AALA, R5F10E8CALA, R5F10E8DALA, R5F10E8EALA R5F10EBAANA, R5F10EBCANA, R5F10EBDANA, R5F10EBEANA R5F10EGAAFB, R5F10EGCAFB, R5F10EGDAFB, R5F10EGEAFB R5F10EGAANA, R5F10EGCANA, R5F10EGDANA, R5F10EGEANA

R5F10ELCAFB, R5F10ELDAFB, R5F10ELEAFB R5F10ELCABG, R5F10ELDABG, R5F10ELEABG

G: Industrial applications When $T_A = -40$ to $+105^{\circ}$ C products is used in the range of $T_A = -40$ to $+85^{\circ}$ C

R5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNA R5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFB R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EV_{DD0} or EV_{SS0} pin, replace EV_{DD0} with V_{DD}, or replace EV_{SS0} with V_{SS}.

2.1 Absolute Maximum Ratings

Absolute Maximum Ratings ($T_A = 25^{\circ}C$) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.5 to +6.5	V
	EV _{DD0}		-0.5 to +6.5	V
	AVDD		-0.5 to +4.6	V
	AVREFP		-0.3 to AV _{DD} +0.3 ^{Note 3}	V
	EVsso		-0.5 to +0.3	V
	AVss		-0.5 to +0.3	V
	AVREFM		-0.3 to AV _{DD} +0.3 ^{Note 3} and AV _{REFM} ≤ AV _{REFP}	V
REGC pin input voltage	Virego	REGC	-0.3 to +2.8 and -0.3 to V _{DD} +0.3 ^{Note 1}	V
Input voltage	VII	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	-0.3 to EV _{DD0} +0.3 and -0.3 to V _{DD} +0.3 ^{Note 2}	V
	Vı2	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} +0.3 ^{Note 2}	V
	V _{I4}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Output voltage	Vo ₁	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	-0.3 to EV _{DD0} +0.3 ^{Note 2}	V
	V _{O2}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Analog input voltage	V _{Al1}	ANI16 to ANI30	-0.3 to EV _{DD0} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	V
	V _{Al2}	ANI0 to ANI12	-0.3 to AV _{DD} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	V

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
 - 2. Must be 6.5 V or lower.
 - 3. Must be 4.6 V or lower.
 - **4.** Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - **2.** AV_{REF(+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage

Absolute Maximum Ratings ($T_A = 25$ °C) (2/2)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	-40	mA
		Total of all pins –170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	-70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P70 to P77,	-100	mA
	Iон ₂	Per pin	P20 to P27, P150 to P154	-0.1	mA
		Total of all pins		-1.3	mA
Output current, low	lo _{L1}	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	40	mA
		Total of all pins 170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P60 to P63, P70 to P77	100	mA
	lo _{L2}	Per pin	P20 to P27, P150 to P154	0.4	mA
		Total of all pins		6.4	mA
Operating ambient	TA	In normal operation	on mode	-40 to +85	°C
temperature		In flash memory p	n flash memory programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/crystal resonator	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	1.0		20.0	MHz
frequency (fx) ^{Note}		$2.4~\textrm{V} \leq \textrm{V}_\textrm{DD} < 2.7~\textrm{V}$	1.0		16.0	MHz
		$1.8 \text{ V} \le \text{V}_{DD} < 2.4 \text{ V}$	1.0		8.0	MHz
		$1.6 \text{ V} \le \text{V}_{DD} < 1.8 \text{ V}$	1.0		4.0	MHz
XT1 clock oscillation frequency (fx) ^{Note}	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. See AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

<R> Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

2.2.2 On-chip oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

Oscillators	Parameters		MIN.	TYP.	MAX.	Unit	
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1		32	MHz
High-speed on-chip oscillator clock frequency accuracy		–20 to +85 °C	1.8 V ≤ V _{DD} ≤ 3.6 V	-1.0		+1.0	%
			1.6 V ≤ V _{DD} < 1.8 V	-5.0		+5.0	%
		–40 to –20 °C	1.8 V ≤ V _{DD} ≤ 3.6 V	-1.5		+1.5	%
			1.6 V ≤ V _{DD} < 1.8 V	-5.5		+5.5	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of HOCODIV register.
 - **2.** This indicates the oscillator characteristics only. See AC Characteristics for instruction execution time.

2.3 DC Characteristics

2.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

(1/5)

Items	Symbol	Conditions	_	MIN.	TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	1.6 V ≤ EV _{DD0} ≤ 3.6 V			-10.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120, 2.7 V ≤ EV _{DD0} ≤ 3.6 V	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			-10.0	mA
		P130, P140, P141	.8 V ≤ EV _{DDO} < 2.7 V -5.0		-5.0	mA	
		(When duty ≤ 70% ^{Note 3})	1.6 V ≤ EV _{DD0} < 1.8 V			-2.5	mA
		Total of P05, P06, P10 to P16, P30,	$2.7~V \leq EV_{DD0} \leq 3.6~V$			-19.0	mA
		P31, P50, P51, P70 to P77,	1.8 V ≤ EV _{DD0} < 2.7 V	mA			
		(When duty ≤ 70% ^{Note 3})	1.6 V ≤ EV _{DD0} < 1.8 V	-5.0	-5.0	mA	
1		Total of all pins (When duty ≤ 70% ^{Note 3})	1.6 V ≤ EV _{DD0} ≤ 3.6 V			-29.0	mA
	І он2	Per pin for P20 to P27, P150 to P154	$1.6 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			-0.1 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			-1.3	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DDO}, V_{DD} pins to an output pin.
 - 2. However, do not exceed the total current value.
 - 3. Specification under conditions where the duty factor ≤ 70%.
 The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = $(I_{OH} \times 0.7)/(n \times 0.01)$ <Example> Where n = 80% and I_{OH} = -10.0 mA Total output current of pins = $(-10.0 \times 0.7)/(80 \times 0.01) \cong -8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.

$(T_A = -40 \text{ to } +85$	°C, 1.6 V ≤	$AV_{DD} \leq V_{DD} \leq 3.6 \text{ V}, 1.6 \text{ V} \leq EV_{DD0} \leq 3.6 \text{ V}$	$V_{DD0} \le V_{DD} \le 3.6 \text{ V}, \text{ Vss} = \text{EVss}_0 = 0 \text{ V}$					
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit	
Output current, low ^{Note 1}	I _{OL1}	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141				20.0 ^{Note 2}	mA	
		Per pin for P60 to P63				15.0 ^{Note 2}	mA	
		Total of P00 to P04, P40 to P43, P120,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			15.0	mA	
		(When duty ≤ 70% ^{Note 3}) Total of P05, P06, P10 to P16, P30, P31, P50, P51, P60 to P63,	$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			9.0	mA	
			1.6 V ≤ EV _{DD0} < 1.8 V			4.5	mA	
			2.7 V ≤ EV _{DD0} ≤ 3.6 V			35.0	mA	
			1.8 V ≤ EV _{DD0} < 2.7 V			20.0	mA	
		P70 to P77 (When duty ≤ 70% ^{Note 3})	1.6 V ≤ EV _{DD0} < 1.8 V			10.0	mA	
lo _{L2}		Total of all pins (When duty ≤ 70% ^{Note 3})				50.0	mA	
	lo _{L2}	Per pin for P20 to P27, P150 to P154				0.4 ^{Note 2}	mA	
		Total of all pins (When duty ≤ 70% ^{Note 3})	1.6 V ≤ AV _{DD} ≤ 3.6 V			5.2	mA	

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVsso and Vss pin.

- 2. However, do not exceed the total current value.
- 3. Specification under conditions where the duty factor ≤ 70%.
 The output current value that has changed to the duty factor > 70% the duty ratio can can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = $(loL \times 0.7)/(n \times 0.01)$ <Example> Where n = 80% and loL = 10.0 mA Total output current of pins = $(10.0 \times 0.7)/(80 \times 0.01) \cong 8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

0

0

0

0

0.32

 $0.3AV_{\text{DD}}$

0.3EVDD0

 $0.2 V_{\text{DD}}$

V

V

V

(3/5)

Symbol MIN. TYP. MAX. Unit Items Conditions Input voltage, V_{IH1} P00 to P06, P10 to P16, P30, P31, Normal input buffer 0.8EVDD0 EV_{DD0} ٧ P40 to P43, P50, P51, P70 to P77, high P120, P140, P141 V_{IH2} P01, P03, P04, P10, P11, TTL input buffer 2.0 EV_{DD0} ٧ $3.3~V \leq EV_{DD0} \leq 3.6~V$ P13 to P16, P43 TTL input buffer EV_{DD0} 1.5 $1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}$ V_{IH3} P20 to P27, P150 to P154 $0.7AV_{\text{DD}}$ AV_{DD} V V_{IH4} P60 to P63 0.7EVDD0 V 6.0 V_{IH5} P121 to P124, P137, EXCLK, EXCLKS, RESET $0.8V_{\text{DD}}$ V_{DD} ٧ P00 to P06, P10 to P16, P30, P31, Input voltage, low V_{IL1} Normal input buffer 0 0.2EVDD0 V P40 to P43, P50, P51, P70 to P77, P120, P140, P141 V_{IL2} P01, P03, P04, P10, P11, TTL input buffer 0 0.5 V

 $3.3 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$ TTL input buffer

 $1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}$

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le AV_{DD} \le V_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = EV_{SS0} = 0 \text{ V})$

P13 to P16, P43

P60 to P63

P20 to P27, P150 to P154

V_{IL3}

 V_{IL4}

VIL5

Caution The maximum value of V_{IH} of pins P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 is EV_{DD0}, even in the N-ch open-drain mode.

P121 to P124, P137, EXCLK, EXCLKS, RESET

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le AV_{DD} \le V_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = EV_{SS0} = 0 \text{ V})$ (4/5)Items Symbol Conditions TYP. MAX. Unit MIN. Output voltage, P00 to P06, P10 to P16, P30, P31, $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ V_{OH1} EVDD0 -٧ P40 to P43, P50, P51, P70 to P77, $I_{OH1} = -2.0 \text{ mA}$ high 0.6 P120, P130, P140, P141 $1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ EV_{DD0} -٧ $I_{OH1} = -1.5 \text{ mA}$ 0.5 $1.6~V \leq EV_{\text{DD0}} \leq 3.6~V,$ V EVDD0 - $I_{OH1} = -1.0 \text{ mA}$ 0.5 P20 to P27, P150 to P154 $1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V},$ AV_{DD} -V V_{OH2} $I_{OH2} = -100 \mu A$ 0.5 V_{OL1} Output voltage, $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ V P00 to P06, P10 to P16, P30, P31, 0.6 low P40 to P43, P50, P51, P70 to P77, $I_{OL1} = 3.0 \text{ mA}$ P120, P130, P140, P141 $2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ 0.4 I_{OL1} = 1.5 mA $1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ 0.4 $I_{OL1} = 0.6 \text{ mA}$ $1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ ٧ 0.4 $I_{OL1} = 0.3 \text{ mA}$ V_{OL2} P20 to P27, P150 to P154 $1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V},$ V 0.4 $I_{OL2} = 400 \mu A$ $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ Vol3 P60 to P63 V 0.4 $I_{OL3} = 3.0 \text{ mA}$ $1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ 0.4 V I_{OL3} = 2.0 mA $1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ ٧

Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.

lol3 = 1.0 mA

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

0.4

Input leakage

On-chip pull-up

resistance

current, low

ILIL1

I_{LIL2}

I_{LIL3}

ILIL4

Rυ

(5/5)

-1

-1

-1

-10

-1

100

 μA

μΑ

 μA

 μA

μΑ

kΩ

Items Symbol Conditions TYP. MAX. Unit Input leakage $V_I = EV_{DD0}$ I_{LIH1} P00 to P06, P10 to P16, P30, μΑ current, high P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P140, P141 P137, RESET $V_{I} = V_{DD}$ I_{LIH2} μΑ Інз P121 to P124 $V_I = V_{DD}$ In input port or μΑ (X1, X2, XT1, XT2, EXCLK, external clock EXCLKS) input In resonator 10 μΑ connection I_{LIH4} P20 to P27, P150 to P154 $V_I = AV_{DD}$ μΑ

VI = EVSSO

VI = VSS

 $V_I = V_{SS}$

VI = AVSS

V_I = EV_{SS0}, In input port

In input port or

external clock input

In resonator

connection

10

20

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le AV_{DD} \le V_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = EV_{SS0} = 0 \text{ V})$

P00 to P06, P10 to P16,

(X1, X2, XT1, XT2, EXCLK,

P20 to P27, P150 to P154

P00 to P06, P10 to P16, P30,

P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141

P30, P31, P40 to P43, P50, P51, P60 to P67, P70 to P77, P120, P140, P141

P137, RESET

P121 to P124

EXCLKS)

2.3.2 Supply current characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

(1/3)

Parameter	Symbol	Conditions						TYP.	MAX.	Unit
Supply current ^{Note 1}	I _{DD1}	Operating mode	HS (high-speed main) mode ^{Note 5}	f _{IH} = 32 MHz ^{Note 3}	Basic operation	V _{DD} = 3.0 V		2.1		mA
					Normal operation	V _{DD} = 3.0 V		4.6	7.0	m/
				f _{IH} = 24 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		3.7	5.5	m/
				f _{IH} = 16 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		2.7	4.0	m/
			LS (low-speed main) mode ^{Note 5}	f _{IH} = 8 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		1.2	1.8	m/
						$V_{DD} = 2.0 \text{ V}$		1.2	1.8	
			LV (Low-voltage	voltage ode $^{\text{Note 5}}$ $f_{\text{IH}} = 4 \text{ MHz}^{\text{Note 3}}$ $Operation$ O		V _{DD} = 3.0 V		1.2	1.7	m/
			main) mode ^{Note 5}			1.2	1.7			
			HS (high-speed main) mode ^{Note 5}	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$	Normal operation	Square wave input		3.0	4.6	m
						Resonator connection		3.2	4.8	
				Resonator	Square wave input		1.9	2.7	m	
						Resonator connection		1.9	2.7	
			LS (low-speed main) mode ^{Note 5}	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$ $f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 2.0 \text{ V}$	Normal operation	Square wave input		1.1	1.7	m.
						Resonator connection		1.1	1.7	
					Normal operation	Square wave input		1.1	1.7	m/
						Resonator connection		1.1	1.7	
			Subsystem clock mode	f _{SUB} = 32.768 kHz ^{Note 4} T _A = -40°C	Normal operation	Square wave input		4.1	4.9	μ
						Resonator connection		4.2	5.0	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +25°C	Normal operation	Square wave input		4.2	4.9	μ
						Resonator connection		4.3	5.0	
				fsub = 32.768 kHz ^{Note 4} TA = +50°C fsub = 32.768 kHz ^{Note 4} TA = +70°C	Normal operation Normal operation	Square wave input		4.3	5.5	μP
						Resonator connection		4.4	5.6	
						Square wave input		4.5	6.3	μ
						Resonator connection		4.6	6.4	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +85°C	Normal operation	Square wave input		4.8	7.7	μ
						Resonator connection		4.9	7.8	

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDDO, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDDO or Vss, EVsso. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, on-chip pull-up/pull-down resistors, and data flash rewriting.
 - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 3. When high-speed system clock and subsystem clock are stopped.
 - **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1). Not including the current flowing into the RTC, 12-bit interval timer and watchdog timer
 - **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: VDD = 2.7 V to 3.6 V@1 MHz to 32 MHz

V_{DD} = 2.4 V to 3.6 V@1 MHz to 16 MHz

LS (low-speed main) mode: $V_{DD} = 1.8 \text{ V to } 3.6 \text{ V@1 MHz to } 8 \text{ MHz}$ LV (Low-voltage main) mode: $V_{DD} = 1.6 \text{ V to } 3.6 \text{ V@1 MHz to } 4 \text{ MHz}$

- **Remarks 1.** fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$ (2/3)

Parameter	Symbol	1.0 4 2 E V	/DD0 ≤ VDD ≤ 3.6 V	MIN.	TYP.	MAX.	Unit		
Supply current ^{Note 1}	DD2Note 2	HALT mode	HS (high-speed main) mode ^{Note 7}	f _{IH} = 32 MHz ^{Note 4}	V _{DD} = 3.0 V		0.54	1.63	mA
				f _{IH} = 24 MHz ^{Note 4}	V _{DD} = 3.0 V		0.44	1.28	mA
				fin = 16 MHz ^{Note 4}	V _{DD} = 3.0 V		0.40	1.00	mA
			LS (low-speed main) mode ^{Note 7}	f _{IH} = 8 MHz ^{Note 4}	V _{DD} = 3.0 V		270	530	μΑ
					V _{DD} = 2.0 V		270	530	·
			LV (Low-voltage main) mode ^{Note 7}	f _{IH} = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		435	640	μΑ
					V _{DD} = 2.0 V		435	640	·
			HS (high-speed main) mode ^{Note 7}	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.00	mA
				V _{DD} = 3.0 V	Resonator connection		0.45	1.17	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	0.60	mA
				V _{DD} = 3.0 V	Resonator connection		0.26	0.67	
			LS (low-speed main) mode ^{Note 7}	$f_{MX} = 8 \text{ MHz}^{\text{Note 3}},$ $V_{DD} = 3.0 \text{ V}$	Square wave input		95	330	μΑ
					Resonator connection		145	380	
				$f_{MX} = 8 \text{ MHz}^{\text{Note 3}},$ $V_{DD} = 2.0 \text{ V}$	Square wave input		95	330	μΑ
					Resonator connection		145	380	
			Subsystem clock mode	$f_{SUB} = 32.768 \text{ kHz}^{Note 5}$ $T_{A} = -40^{\circ}\text{C}$ $f_{SUB} = 32.768 \text{ kHz}^{Note 5}$ $T_{A} = +25^{\circ}\text{C}$ $f_{SUB} = 32.768 \text{ kHz}^{Note 5}$ $T_{A} = +50^{\circ}\text{C}$	Square wave input		0.25	0.57	μΑ
					Resonator connection		0.44	0.76	
					Square wave input		0.30	0.57	μΑ
					Resonator connection		0.49	0.76	
					Square wave input		0.38	1.17	μΑ
					Resonator connection		0.57	1.36	
				$f_{SUB} = 32.768 \text{ kHz}^{\text{Note 5}}$ $T_A = +70^{\circ}\text{C}$	Square wave input		0.52	1.97	μΑ
					Resonator connection		0.71	2.16	
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.97	3.37	μΑ
	I _{DD3} Note 6			T _A = +85°C	Resonator connection		1.16	3.56	
		STOP mode ^{Note 8}	T _A = -40°C				0.16	0.50	μΑ
			T _A = +25°C				0.23	0.50	
			$T_A = +50^{\circ}C$ $T_A = +70^{\circ}C$				0.34	1.10	
							0.46	1.90	
			T _A = +85°C		0.75	3.30			

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, on-chip pull-up/pull-down resistors, and data flash rewriting.
 - 2. During HALT instruction execution by flash memory.
 - 3. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 4. When high-speed system clock and subsystem clock are stopped.
 - **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). Including the current flowing into the RTC. However, not including the current flowing into the 12-bit interval timer, and watchdog timer.
 - **6.** When subsystem clock is stopped. Not including the current flowing into the RTC, 12-bit interval timer, watchdog timer.
 - **7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V} @1 \text{ MHz}$ to 32 MHz

 $2.4 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V@1 MHz to 16 MHz}$

LS (low-speed main) mode: 1.8 $V \le V_{DD} < 3.6 V@1$ MHz to 8 MHz LV (low-voltage main) mode: 1.6 $V \le V_{DD} \le 3.6 V@1$ MHz to 4 MHz

- **8.** Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - **4.** Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is T_A = 25°C



 $(T_A = -40 \text{ to } +85^{\circ}\text{C}. \ 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}. \text{ Vss} = \text{EV}_{SS0} = 0 \text{ V})$ <R>

$(T_A = -40 \text{ to } +85^{\circ}\text{C})$, 1.6 V ≤ EVDD	$00 \le V_{DD} \le 3.6 V$	Vss = EVss0 = 0 V)				(3/3
Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	_{FIL} Note 1				0.20		μΑ
RTC operating current	IRTC Notes 1, 2, 3				0.02		μА
12-bit interval timer operating current	I _{IT} Notes 1, 2, 4				0.02		μΑ
Watchdog timer operating current	_{WDT} Notes 1, 2, 5	f∟ = 15 kHz	fil = 15 kHz				
A/D converter operating current	ADC Notes 6, 7	AV _{DD} = 3.0 V, W	hen conversion at maximum speed		420	720	μА
AV _{REF(+)} current	AVREFNote 8	AV _{DD} = 3.0 V, A[DREFP1 = 0, ADREFP0 = 0 ^{Note 7}		14.0	25.0	μА
		AV _{REFP} = 3.0 V, A		14.0	25.0	μА	
		ADREFP1 = 1, A		14.0	25.0	μА	
A/D converter reference voltage current	ADREF Notes 1, 9	V _{DD} = 3.0 V		75.0		μΑ	
Temperature sensor operating current	TMPNote 1	V _{DD} = 3.0 V			75.0		μΑ
LVD operating current	I _{LVD} Notes 1, 11				0.08		μА
BGO operating current	I _{BGO} Notes 1, 12				2.5	12.2	mA
Self-programming operating current	FSPNotes 1, 13				2.5	12.2	mA
SNOOZE operating current	Isnoz	A/D converter operation (AV _{DD} = 3.0 V)	The mode is performed ^{Notes 1, 14}		0.50	0.60	mA
			During A/D conversionNote 1		0.60	0.75	mA
			During A/D conversionNote 7		420	720	μΑ
		CSI/UART opera	ation ^{Note 1}		0.70	0.84	mA

(Notes and Remarks are listed on the next page.)

<R> Notes 1. Current flowing to VDD.

- 2. When high-speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2, or IDD3 and IWDT when the watchdog timer is in operation.
- 6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC, IAVREF, IADREF when the A/D converter operates in an operation mode or the HALT mode.
- 7. Current flowing to the AVDD.
- 8. Current flowing from the reference voltage source of A/D converter.
- 9. Operation current flowing to the internal reference voltage.
- 10. Current flowing to the AVREFP.
- **11.** Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
- 12. Current flowing only during data flash rewrite.
- 13. Current flowing only during self programming.
- Remarks 1. fil.: Low-speed on-chip oscillator clock frequency
 - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 3. fclk: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is TA = 25°C

2.4 AC Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, AV_{DD} \le V_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = EV_{SS0} = 0 \text{ V})$

TA = -40 to +85°C, AVDE Items	Symbol		Condi		, , , , , , , , , , , , , , , , , , , ,	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Tcy	Main system	HS (high-s	peed	$2.7 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	0.03125		1	μs
instruction execution time)		clock (f _{MAIN}) operation	main) mod	•	2.4 V ≤ V _{DD} < 2.7 V	+		1	μs
			LS (low-sp		$1.8 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	0.125		1	μs
			LV (low-vo	•	1.6 V ≤ V _{DD} ≤ 3.6 V	0.25		1	μs
		Subsystem clock (fsub) operation		1.8 V ≤ V _{DD} ≤ 3.6 V	28.5	30.5	31.3	μs	
		In the self programming mode	,		$2.7 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	0.03125		1	μs
				е	$2.4 \text{ V} \le \text{V}_{DD} \le 2.7 \text{ V}$	0.0625		1	μs
				$1.8 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	0.125		1	μs	
			LV (low-vo main) mod	•	$1.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	0.25		1	μs
External system clock	fex	$2.7 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}$			1.0		20.0	MHz	
frequency		2.4 V ≤ V _{DD} < 2.7 V			1.0		16.0	MHz	
		1.8 V ≤ V _{DD} < 2.4 V			1.0		8.0	MHz	
		$1.6 \text{ V} \le \text{V}_{DD} < 1.8 \text{ V}$				1.0		4.0	MHz
	fexs					32		35	kHz
External system clock input	texh, texl	$2.7 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$				24			ns
high-level width, low-level width		2.4 V ≤ V _{DD} < 2.7 V				30			ns
		$1.8 \text{ V} \le \text{V}_{DD} < 2.4 \text{ V}$				60			ns
		1.6 V ≤ V _{DD} < 1.8 V				120			ns
	texhs, texhs	S							μs
TI00, TI01, TI03 to TI07 input high-level width, low-level width	tтін, tтіL					1/fмск+10			ns ^{Note}
TO00, TO01, TO03 to	fтo	HS (high-speed main) mode		2.7 V	$\leq EV_{DD0} \leq 3.6 \text{ V}$			8	MHz
TO07 output frequency				1.8 V ≤ EV _{DD0} < 2.7 V				4	MHz
				1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
		LS (low-speed main) mode		1.8 V ≤ EV _{DD0} ≤ 3.6 V				4	MHz
				1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
		LV (low-voltage main) mode		1.6 V	\leq EV _{DD0} \leq 3.6 V			2	MHz
PCLBUZ0, PCLBUZ1	f _{PCL}	HS (high-spee	ed main)	2.7 V	\leq EV _{DD0} \leq 3.6 V			8 N 4 N 2 N 4 N 2 N 2 N	MHz
output frequency		mode		1.8 V	≤ EV _{DD0} < 2.7 V			4	MHz
				1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
		LS (low-speed main) mode		1.8 V	\leq EV _{DD0} \leq 3.6 V			4	MHz
				1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
		LV (low-voltag	ge main)	1.8 V	\leq EV _{DD0} \leq 3.6 V			4	MHz
		mode		1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
Interrupt input high-level	tinth, tintl	INTP0		1.6 V	$\leq V_{DD} \leq 3.6 \text{ V}$	1			μs
width, low-level width		INTP1 to INT	P11	1.6 V	$\leq EV_{DD0} \leq 3.6~V$	1			μs
Key interrupt input high-level width, low-level	tkr	KR0 to KR9			\leq EV _{DD0} \leq 3.6 V, \leq AV _{DD0} \leq 3.6 V	250			ns
width					≤ EV _{DD0} < 1.8 V, ≤ AV _{DD0} < 1.8 V	1			μs
	trsl			_		10			

(Note and Remark are listed on the next page.)



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Note The following conditions are required for low-voltage interface when EV_{DD0} < V_{DD}.

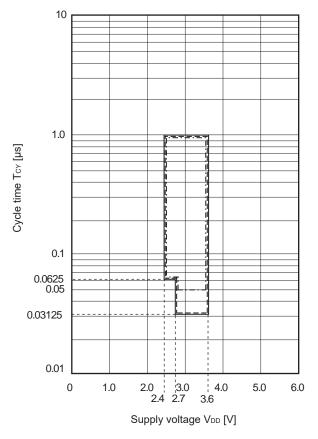
 $1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V} : \text{MIN. } 125 \text{ ns}$ $1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V} : \text{MIN. } 250 \text{ ns}$

Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer clock select register 0 (TPS0) and timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation

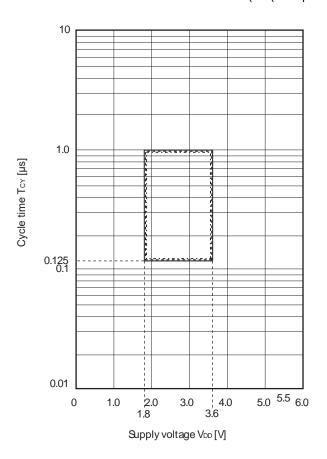
Tcy vs VDD (HS (high-speed main) mode)



- When the high-speed on-chip oscillator clock is selected
- --- During self programming
- --- When high-speed system clock is selected

<R>

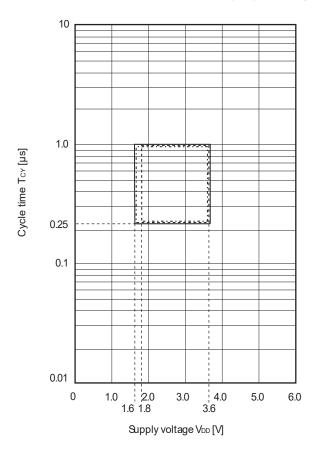
Tcy vs Vdd (LS (low-speed main) mode)



- When the high-speed on-chip oscillator clock is selected
- --- During self programming
- --- When high-speed system clock is selected

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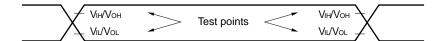
Tcy vs Vdd (LV (low-voltage main) mode)



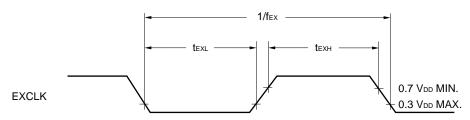
- When the high-speed on-chip oscillator clock is selected
- --- During self programming
- --- When high-speed system clock is selected

AC Timing Test Points

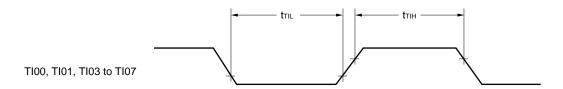


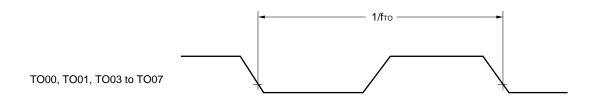


External System Clock Timing

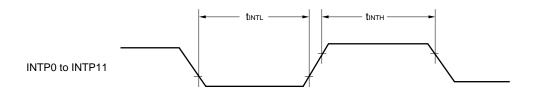


<R> TI/TO Timing

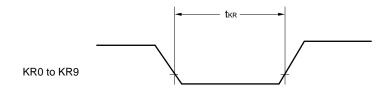




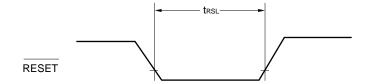
Interrupt Request Input Timing



Key Interrupt Input Timing



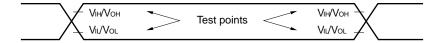
RESET Input Timing



2.5 Peripheral Functions Characteristics

AC Timing Test Points





2.5.1 Serial array unit

(1) During communication at same potential (UART mode)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Parameter	Symbol	Conditions	HS	Note 1	LS ^t	Note 2	LV	Note 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rateNote 4		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note \ 6}$		5.3 ^{Note 5}		1.3		0.6	Mbps
		1.8 V ≤ EV _{DD} ≤ 3.6 V		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note \ 6}$		5.3 ^{Note 5}		1.3		0.6	Mbps
		1.7 V ≤ EV _{DD} ≤ 3.6 V		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		5.3 ^{Note 5}		1.3 ^{Note 5}		0.6	Mbps
		1.6 V ≤ EV _{DD} ≤ 3.6 V		-		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		-		1.3 ^{Note 5}		0.6	Mbps

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. Transfer rate in the SNOOZE mode is 4800 bps.
- **5.** The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$.

 $2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MAX. 2.6 Mbps $1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 2.4 \text{ V}$: MAX. 1.3 Mbps

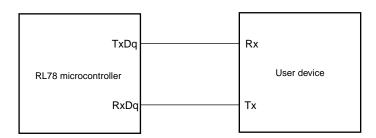
 $1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V} : \text{MAX. } 0.6 \text{ Mbps}$

6. fclk in each operating mode is as below.

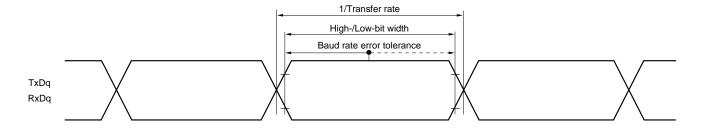
HS (high-speed main) mode: fclk = 32 MHz LS (low-speed main) mode: fclk = 8 MHz LV (low-voltage main) mode: fclk = 4 MHz

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

2. fmck: Serial array unit operation clock frequency(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,n: Channel number (mn = 00 to 03, 10, 11))

(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Parameter	Symbol	Condition	s	HS ^{Note 1}		LS ^{Note 2}		LV ^{Note 3}		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	$2.7~V \le EV_{DD} \le 3.6~V$	tkcy1 ≥ 2/fclk	83.3		250		500		ns
SCKp high-/low-level width	tkH1, tkL1	2.7 V ≤ EV _{DD} ≤ 3.6 V		tkcy1/2 -10		tксү1/2 -50		tkcy1/2 -50		ns
SIp setup time (to SCKp↑)Note 4	tsıĸ1	2.7 V ≤ EV _{DD} ≤ 3.6 V		33		110		110		ns
SIp hold time (from SCKp↑)Note 4	t KSI1	2.7 V ≤ EV _{DD} ≤ 3.6 V		10		10		10		ns
Delay time from SCKp↓ to SOp output ^{Note 5}	tkso1	C = 20 pF ^{Note 6}			10		10		10	ns

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 6. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM numbers (g = 1)

2. fmck: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
n: Channel number (mn = 00))

(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DDO} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SSO} = 0 \text{ V})$

Parameter	Symbol	Conditions	S	HS ^t	Note 1	LS ^N	lote 2	LV	lote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy2	2.7 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	125		500		1000		ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	250		500		1000		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fcLK	500		500		1000		ns
		$1.7~\text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6~\text{V}$	tkcy1 ≥ 4/fclk	1000		1000		1000		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	-		1000		1000		ns
SCKp high-/low-level width	t _{KH2} ,	2.7 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -18		tксү2/2 -50		tксү2/2 -50		ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -38		tксү2/2 -50		tксү2/2 -50		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -50		tксү2/2 -50		tксү2/2 -50		ns
		1.7 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -100		tксү2/2 -100		tксү2/2 -100		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V		_		tксү2/2 -100		tксү2/2 -100		ns
SIp setup time	tsık2	$2.7~\text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6~\text{V}$		44		110		110		ns
(to SCKp↑) ^{Note 4}		$2.4~V \leq EV_{DD0} \leq 3.6~V$		75		110		110		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V		110		110		110		ns
		1.7 V ≤ EV _{DD0} ≤ 3.6 V		220		220		220		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V		_		220		220		ns
SIp hold time	t _{KSI2}	1.7 V ≤ EV _{DD} ≤ 3.6 V		19		19		19		ns
(from SCKp↑)Note 4		$1.6 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$		_		19		19		ns
Delay time from SCKp↓	tkso2	$1.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$	$C = 30 \text{ pF}^{\text{Note 6}}$		25		25		25	ns
to SOp outputNote 5		$1.6 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$	$C = 30 pF^{Note 6}$		_		25		25	ns

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **5.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 6. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)

(4) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DDO} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = \text{EV}_{SSO} = 0 \text{ V})$

Parameter	Symbol	С	onditio	ns	HS!	Note 1	LS ^N	lote 2	LV ^N	lote 3	Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time ^{Note 4}	tKCY2	2.7 V ≤ EV _{DD0} ≤	3.6 V	16 MHz < fмск	8/ƒмск		-		_		ns
				fмcк ≤ 16 MHz	6/ƒмск		6/fмск		6/fмск		ns
		2.4 V ≤ EV _{DD0} ≤	3.6 V		6/ƒмск		6/fмск		6/ƒмск		ns
					and 500ns		and 500ns		and 500ns		
		1.8 V ≤ EV _{DD0} ≤	36 V		6/fмск		6/fмск		6/fмск		ns
		1.0 1 = 21000	0.0		and		and		and		110
					750ns		750ns		750ns		
		1.7 V ≤ EV _{DD0} ≤	3.6 V		6/fмск		6/fмск		6/fмск		ns
					and 1500ns		and 1500ns		and 1500ns		
		1.6 V ≤ EV _{DD0} ≤	261/		1300118		6/fmck		6/fmck		no
		1.0 V ≤ E V DD0 ≤	3.0 V		_		and		and		ns
							1500ns		1500ns		
SCKp high-/low-level	tĸH2,	2.7 V ≤ EV _{DD} ≤	3.6 V		tkcy2/2		tkcy2/2		tkcy2/2		ns
width	t _{KL2}				-8		-8		-8		
		1.8 V ≤ EV _{DD0} ≤	3.6 V		tkcy2/2		tkcy2/2		tkcy2/2		ns
					-18		-18		-18		
		1.7 V ≤ EV _{DD0} ≤	3.6 V		tксү2/2 -66		tkcy2/2 -66		tксү2/2 -66		ns
		1.6 V ≤ EV _{DD0} ≤	261/		-00		-00 tксу2/2		-00 tксу2/2		no
		1.0 V ≤ E V DD0 ≤	3.0 V		_		-66		-66		ns
SIp setup time	tsik2	2.7 V ≤ EV _{DD0} ≤	3.6 V		1/fмск		1/fмск		1/ f мск		ns
(to SCKp↑) ^{Note 5}					+20		+30		+30		
		1.8 V ≤ EV _{DD0} ≤	3.6 V		1/fмск		1/fмск		1/fмск		ns
					+30		+30		+30		
		1.7 V ≤ EV _{DD0} ≤	3.6 V		1/fмск		1/fмск		1/fмск		ns
		40)/ (5)/			+40		+40		+40		
		1.6 V ≤ EV _{DD0} ≤	3.6 V		_		1/fмск +40		1/fмск +40		ns
Slp hold time	t _{KSI2}	1.8 V ≤ EV _{DD0} ≤	36 V		1/ƒмск		1/ƒмск		1/fмск		ns
(from SCKp↑) ^{Note 5}	ENGIZ	1.0 1 = 21000	0.0		+31		+31		+31		110
		1.7 V ≤ EV _{DD0} ≤	3.6 V		1/fмск+		1/f _{MCK} +		1/f _{MCK} +		ns
					250		250		250		
		1.6 V ≤ EV _{DD0} ≤	3.6 V		_		1/f _{MCK} +		1/f _{MCK} +		ns
			ı				250		250		
Delay time from SCKp↓ to SOp output ^{Note 6}	tkso2	C = 30 pF ^{Note 7}	2.7 V	≤ EV _{DD0} ≤ 3.6 V		2/fмcк		2/fмcк		2/fмcк	ns
to SOp output			0.41/	(F)/ (00)/		+44		+110		+110	
			2.4 V	≤ EV _{DD0} ≤ 3.6 V		2/fмск +75		2/fмск +110		2/fмск +110	ns
			1 8 V	≤ EV _{DD0} ≤ 3.6 V		2/fмск		2/fмск		2/fмск	ns
				• • • • • • • • • • • • • • • • • •		+110		+110		+110	
			1.7 V	≤ EV _{DD0} ≤ 3.6 V		2/fмск		2/fмск		2/fмск	ns
						+220		+220		+220	
			1.6 V	≤ EV _{DD0} ≤ 3.6 V		-		2/fмск		2/fмск	ns
								+220		+220	

(Note, Caution and Remark are listed on the next page.)



- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - **5.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **6.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 7. C is the load capacitance of the SOp output lines.

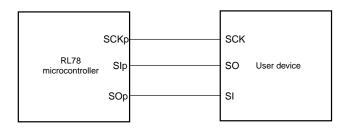
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1)
 - 2. fmck: Serial array unit operation clock frequency

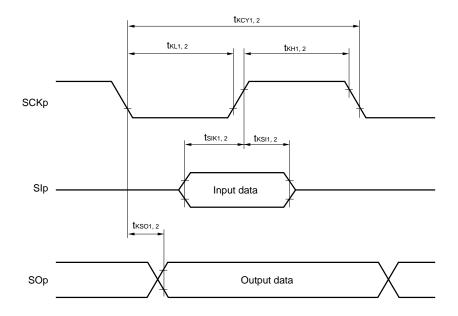
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

 n: Channel number (mn = 00 to 03, 10, 11))

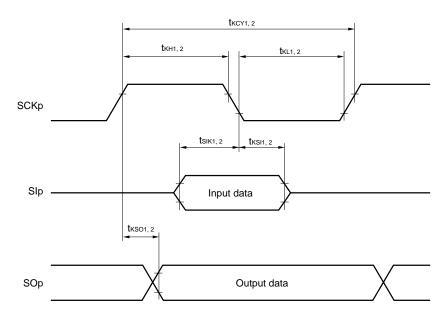
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21)

2. m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)

(5) During communication at same potential (simplified I^2C mode) (1/2) (T_A = -40 to +85°C, 1.6 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, Vss = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	HS	Note 1	LS ^N	lote 2	LV	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$		1000 ^{Note}		400 ^{Note}		400 ^{Note}	kHz
		$1.8~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 100~pF,~R_b = 3~k\Omega$		400 ^{Note 4}		400 ^{Note}		400 ^{Note}	kHz
		1.8 V \leq EV _{DD0} $<$ 2.7 V, C _b = 100 pF, R _b = 5 kΩ		300 ^{Note 4}		300 ^{Note}		300 ^{Note}	kHz
		$1.7 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$		250 ^{Note 4}		250 ^{Note}		250 ^{Note}	kHz
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, \text{ R}_{\text{b}} = 5 \text{ k}\Omega$		-		250 ^{Note}		250 ^{Note}	kHz
Hold time when SCLr = "L"	tLOW	$2.7~V \leq \text{EV}_{\text{DD0}} \leq 3.6~V,$ $C_b = 50~\text{pF},~R_b = 2.7~\text{k}\Omega$	475		1150		1150		ns
			1150		1150		1150		ns
		$1.8 \ V \le EV_{DD0} < 2.7 \ V,$ $C_b = 100 \ pF, \ R_b = 5 \ k\Omega$	1550		1550		1550		ns
		1.7 V \leq EV _{DD0} $<$ 1.8 V, C _b = 100 pF, R _b = 5 kΩ	1850		1850		1850		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 5 \text{ k}\Omega$	-		1850		1850		ns
Hold time when SCLr = "H"	tніgн	$2.7~V \leq \text{EV}_{\text{DD0}} \leq 3.6~V,$ $C_b = 50~\text{pF},~R_b = 2.7~\text{k}\Omega$	475		1150		1150		ns
			1150		1150		1150		ns
		$1.8 \ V \le EV_{DD0} < 2.7 \ V,$ $C_b = 100 \ pF, \ R_b = 5 \ k\Omega$	1550		1550		1550		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 5 \text{ k}\Omega$	1850		1850		1850		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 5 \text{ k}\Omega$	-		1850		1850		ns
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$	1/f _{MCK} + 85 ^{Note 5}		1/f _{MCK} + 145 ^{Note 5}		1/f _{MCK} + 145 ^{Note 5}		ns
		$1.8~V \leq EV_{DD} \leq 3.6~V,$ $C_b = 100~pF,~R_b = 3~k\Omega$	1/f _{MCK} + 145 ^{Note 5}		1/f _{MCK} + 145 ^{Note 5}		1/f _{MCK} + 145 ^{Note 5}		ns
		$1.8 \ V \leq EV_{DD0} < 2.7 \ V,$ $C_b = 100 \ pF, \ R_b = 5 \ k\Omega$	1/f _{MCK} + 230 ^{Note 5}		1/f _{MCK} + 230 ^{Note 5}		1/f _{MCK} + 230 ^{Note 5}		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DD}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 5 \text{ k}\Omega$	1/f _{MCK} + 290 ^{Note 5}		1/f _{MCK} + 290 ^{Note 5}		1/f _{MCK} + 290 ^{Note 5}		ns
		1.6 V \leq EV _{DD0} $<$ 1.8 V, C _b = 100 pF, R _b = 5 kΩ	_		1/f _{MCK} + 290 ^{Note 5}		1/f _{MCK} + 290 ^{Note 5}		ns

(Notes, Caution and Remarks are listed on the next page.)

(5) During communication at same potential (simplified I²C mode) (2/2)

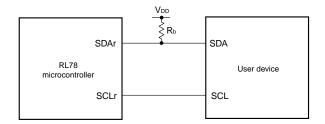
($T_A = -40 \text{ to } +85^{\circ}\text{C}$	$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	$V_{SS} = EV_{SS0} = 0 V$	
	17 70 10 .00 0	v = = = v = v = v = v = v = v	, 400 - 4000 0 4/	

Parameter	Symbol	Conditions	HS ^t	Note 1	LS ^N	lote 2	LV	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data hold time (transmission)	thd:dat	$2.7 \; V \leq EV_{DD0} \leq 3.6 \; V,$ $C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega$	0	305	0	305	0	305	ns
		1.8 V \leq EV _{DD0} \leq 3.6 V, C _b = 100 pF, R _b = 3 kΩ	0	355	0	355	0	355	ns
		1.8 V \leq EV _{DD0} $<$ 2.7 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	ns
		1.7 V \leq EV _{DD0} \leq 1.8 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	ns
		1.6 V \leq EV _{DD0} $<$ 1.8 V, C _b = 100 pF, R _b = 5 kΩ	_	_	0	405	0	405	ns

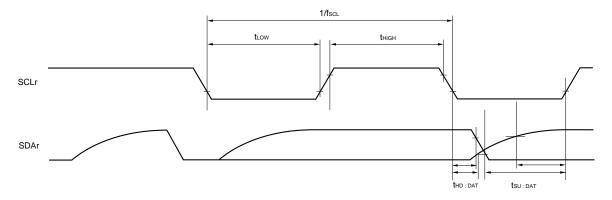
- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. The value must also be fclk/4 or lower.
 - 5. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the normal input buffer and the N-ch open drain output (Vpb tolerance (When 25- to 48-pin products)/EVpb tolerance (When 64-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).

Simplified I²C mode mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** $R_b[\Omega]$: Communication line (SDAr) pull-up resistance, $C_b[F]$: Communication line (SDAr, SCLr) load capacitance
 - 2. r: IIC number (r = 00, 01, 10, 11, 20, 21), g: PIM number (g = 0, 1), h: POM number (h = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number, mn = 00 to 03, 10, 11)

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol		Conditions		HS	Note 1	LS	Note 2	LV'	Note 3	Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer		Reception	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$			fмск/6		fмск/6		fмск/6	bps
rate ^{Note 4}			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 7}$		5.3		1.3		0.6	Mbps
			1.8 V ≤ EV _{DD0} < 3.3 V,			fмск/6		fмск/6		fмск/6	bps
			$1.6~V \leq V_b \leq 2.0~V^{\text{Note 5}}$	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 7}$		5.3 Note 6		1.3		0.6	Mbps

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. Transfer rate in the SNOOZE mode is 4800 bps.
 - 5. Use it with EVDD0≥Vb.
 - 6. The following conditions are required for low-voltage interface when EVDD0 < VDD.

 $2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MAX. 2.6 Mbps $1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 2.4 \text{ V}$: MAX. 1.3 Mbps

7. fclk in each operating mode is as below.

HS (high-speed main) mode: fclk = 32 MHz

LS (low-speed main) mode: fclk = 8 MHz LV (low-voltage main) mode: fclk = 4 MHz

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remarks 1. V_b[V]: Communication line voltage

- **2.** q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
- 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11)

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol		Conditions		HS ^{Note 1}		LS ^{Note 2}		LV ^{Note 3}		Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer		Transmission	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$			Note 4		Note 4		Note 4	bps
rate			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 2.7$ k Ω , $V_b = 2.3$ V		1.2 Note 5		1.2 Note 5		1.2 Note 5	Mbps
			1.8 V ≤ EV _{DD0} < 3.3 V,			Note 7		Note 7		Note 7	bps
			$1.6~V \leq V_b \leq 2.0~V^{\text{Note 6}}$	Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 5.5$ k Ω , $V_b = 1.6$ V		0.43 Note 8		0.43 Note 8		0.43 Note 8	Mbps

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- **4.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV $_{DD0} \leq$ 3.6 V and 2.3 V \leq V $_{b} \leq$ 2.7 V

Maximum transfer rate =
$$\frac{1}{\left\{-C_b \times R_b \times \ln \left(1 - \frac{2.0}{V_b}\right)\right\} \times 3}$$
 [bps]

$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \text{In} \\ \text{Baud rate error (theoretical value)} = \frac{(1 - \frac{2.0}{V_b})\}}{\frac{1}{\text{Transfer rate}} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. See Note 4 above to calculate the maximum transfer rate under conditions of the customer.
- **6.** Use it with $EV_{DD0} \ge V_b$.
- 7. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V \leq EV_{DD0} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

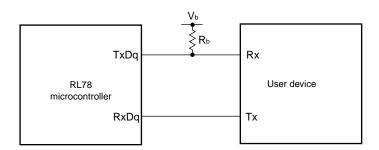
Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{1.5}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

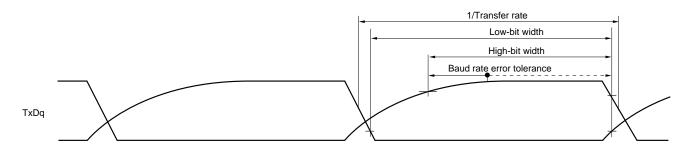
- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **8.** This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 7** above to calculate the maximum transfer rate under conditions of the customer.

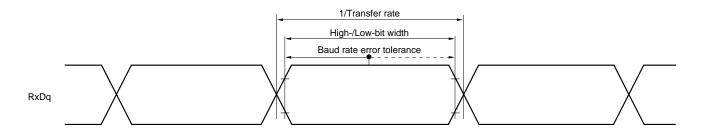
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.** $R_b[\Omega]$: Communication line (TxDq) pull-up resistance,
 - C_b[F]: Communication line (TxDq) load capacitance, V_b[V]: Communication line voltage
 - 2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))

(7) Communication at different potential (2.5 V) (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EV}_{\text{DD}0} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Parameter	Symbol	Conditions		HS ^N	ote 1	LSN	ote 2	LV ^{No}	ote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 20 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	tkcy1 ≥ 2/f cLk	300		1150		1150		ns
SCKp high-level width	t _{KH1}	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$^{\prime}$ \leq V_b \leq 2.7 V ,	tксү1/2 — 120		tксү1/2 — 120		tксү1/2 — 120		ns
SCKp low-level width	t _{KL1}	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$' \le V_b \le 2.7 V$,	tксү1/2 —		tксү1/2 — 50		tксү1/2 — 50		ns
SIp setup time (to SCKp↑) ^{Note 4}	tsıĸ1	$2.7 \text{ V} \le \text{EV}_{\text{DDO}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,	121		479		479		ns
SIp hold time (from SCKp↑) ^{Note 4}	t _{KSI1}	$2.7 \text{ V} \le \text{EV}_{\text{DDO}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,	10		10		10		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso1	$2.7 \text{ V} \le \text{EV}_{\text{DDO}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 5}	tsıĸ1	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$' \le V_b \le 2.7 V$,	33		110		110		ns
SIp hold time (from SCKp↓) ^{Note 5}	t _{KSI1}	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,	10		10		10		ns
Delay time from SCKp↑ to SOp outputNote 5	tkso1	$2.7 \text{ V} \leq \text{EV}_{\text{DDO}} \leq 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,		10		10		10	ns

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 5. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

- **Remarks 1.** Rb[Ω]: Communication line (SCKp, SOp) pull-up resistance, Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
 - 2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)

(8) Communication at different potential (1.8V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions		HS ^N	ote 1	LSN	ote 2	LV ^N	ote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 30 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	tkcy1 ≥ 4/fclk	500		1150		1150		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 4}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	tkcy1 ≥ 4/fclk	1150		1150		1150		ns
SCKp high-level width	tкн1	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$\leq V_b \leq 2.7 V$,	tксу1/2 — 170		tксү1/2 — 170		tксү1/2 — 170		ns
		$\begin{array}{l} 1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \\ 4, \\ C_b = 30 \text{ pF}, \ R_b = 5.5 \text{ k}\Omega \end{array}$	$\leq V_b \leq 2.0~V^{\text{Note}}$	tксу1/2 – 458		tkcy1/2 – 458		tксү1/2 – 458		ns
SCKp low-level width	t _{KL1}	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$\leq V_b \leq 2.7 V$,	tксу1/2 — 18		tксү1/2 — 50		tксү1/2 — 50		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, 1.6 \text{ V} \le 4$, $C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$	$\leq V_b \leq 2.0 \text{ V}^{\text{Note}}$	tксу1/2 — 50		tkcy1/2 – 50		tксү1/2 — 50		ns

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - **4.** Use it with $EV_{DD0} \ge V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remarks 1. R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage

- 2. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
- **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(8) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	HS	Note 1	LS ^t	Note 2	LV	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) ^{Note 4}	tsıĸ1	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	177		479		479		ns
		$\begin{array}{l} 1.8~V \leq EV_{DD0} < 3.3~V,~1.6~V \leq V_b \leq 2.0~V^{\text{Note}} \\ \text{6}, \\ C_b = 30~pF,~R_b = 5.5~k\Omega \end{array}$	479		479		479		ns
SIp hold time (from SCKp↑) ^{Note 4}	t _{KSI1}	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	19		19		19		ns
		$\begin{array}{l} \text{1.8 V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note}} \\ \text{6}, \\ \text{C}_{\text{b}} = 30 \text{ pF}, \ \text{R}_{\text{b}} = 5.5 \text{ k}\Omega \end{array}$	19		19		19		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	t KSO1	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $		195		195		195	ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ \text{6}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$		483		483		483	ns
SIp setup time (to SCKp↓) ^{Note 5}	tsıĸı	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	44		110		110		ns
		$ \begin{array}{l} 1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note}} \\ \text{G}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 5.5 \text{ k}\Omega \end{array} $	110		110		110		ns
SIp hold time (from SCKp↓) ^{Note 5}	t _{KSI1}	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	19		19		19		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ \text{6}, \\ C_b = 30 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{array}$	19		19		19		ns
Delay time from SCKp↑ to SOp outputNote 5	tkso1	$ \begin{array}{c} 2.7 \; \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \; \text{V}, 2.3 \; \text{V} \leq \text{V}_{\text{b}} \leq 2.7 \; \text{V}, \\ C_{\text{b}} = 30 \; \text{pF}, \; R_{\text{b}} = 2.7 \; \text{k} \Omega \\ \end{array} $		25		25		25	ns
		$\begin{array}{l} 1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note}} \\ \text{G}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 5.5 \text{ k}\Omega \end{array}$		25		25		25	ns

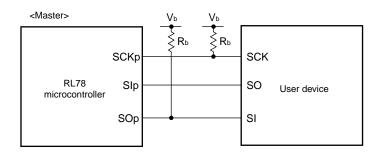
- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 5. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **6.** Use it with $EV_{DD0} \ge V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

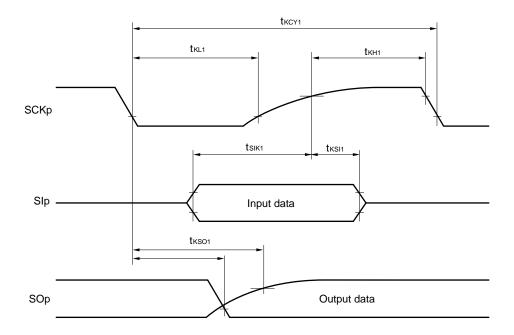


CSI mode connection diagram (during communication at different potential)

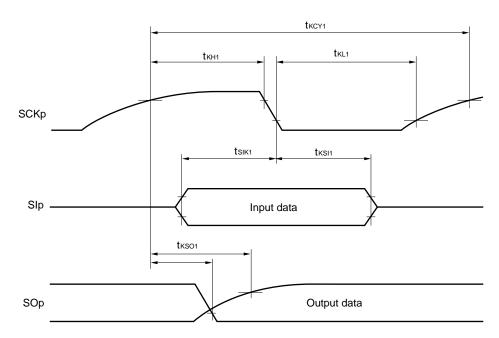


- **Remarks 1.** Rb[Ω]: Communication line (SCKp, SOp) pull-up resistance, Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (m = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(9) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DDO} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SSO} = 0 \text{ V})$

Parameter	Symbol	Cond	ditions	HS ¹	Note 1	LS ^N	Note 2	LV*	lote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle timeNote 4	tkcy2	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$	24 MHz < fmck	20/fмск		_		_		ns
		$2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V}$	20 MHz < fмcк≤24 MHz	16/f мск		_		_		ns
			16 MHz < fмcк≤ 20 MHz	14/fмск		_		_		ns
			8 MHz < fмcк≤ 16 MHz	12/fмск		_		_		ns
			4 MHz < f _{MCK} ≤8 MHz	8/fмск		16/fмск		_		ns
			fмcк≤4 MHz	6/fмск		10/fмск		10/fмск		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$	24 MHz < fmck	48/f мск		_		_		ns
		$1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V}^{\text{Note 5}}$	20 MHz < f _{MCK} ≤ 24 MHz	36/fмск		_		_		ns
			16 MHz < f _{MCK} ≤ 20 MHz	32/fмск		_		_		ns
			8 MHz < fмcк≤ 16 MHz	26/fмск		_		_		ns
			4 MHz < f _{MCK} ≤8 MHz	16/fмск		16/fмск		_		ns
			fmck≤4 MHz	10/fмск		10/fмск		10/fмск		ns
SCKp high-/low-level width	t _{KH2} ,	2.7 V ≤ EV _{DD0} ≤ 3.6 V	$V_{b} \leq 2.3 \text{ V} \leq V_{b} \leq 2.7 \text{ V}$	tkcy2/2 - 18		tkcy2/2 - 50		tkcy2/2 - 50		ns
		1.8 V ≤ EV _{DD0} < 3.3 V	7, $1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V}^{\text{Note}}$	tkcy2/2 - 50		tkcy2/2 - 50		tkcy2/2 - 50		ns
SIp setup time (to SCKp↑)Note 6	tsıк2	2.7 V ≤ EV _{DD0} ≤ 3.6 V	$V_{b} \le 2.3 \text{ V} \le V_{b} \le 2.7 \text{ V}$	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		1.8 V ≤ EV _{DD0} < 3.3 V	$1.6~V \le V_b \le 2.0~V^{\text{Note}}$	1/fмск + 30		1/fмcк + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) ^{Note 6}	tksi2			1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
Delay time from SCKp↓ to SOp output ^{Note 7}	tkso2	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}$			2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
		1.8 V \leq EV _{DD0} $<$ 3.3 V $_{5}$, $_{C_b}$ = 30 pF, $_{R_b}$ = 5.5 k	$V_{b} \leq 2.0 \text{ V}^{\text{Note}}$ Ω		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

Notes 1. HS is condition of HS (high-speed main) mode.

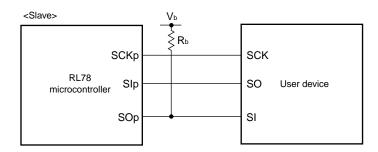
- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
- 5. Use it with $EV_{DD0} \ge V_b$.
- **6.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 7. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

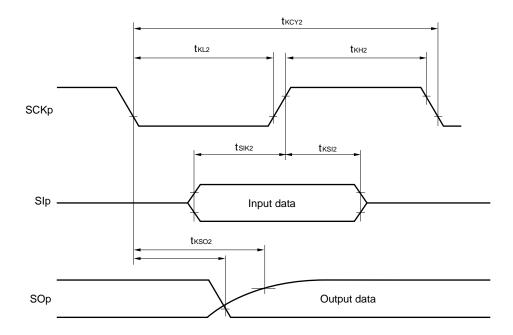
Nov 30, 2016

CSI mode connection diagram (during communication at different potential)

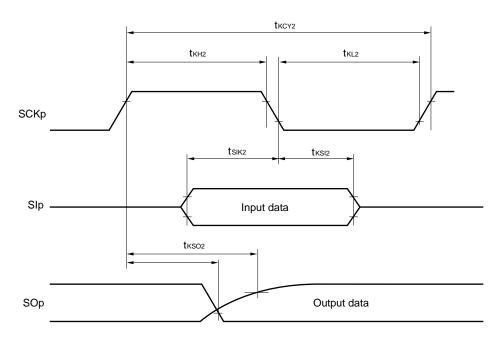


- **Remarks 1.** $R_b[\Omega]$: Communication line (SOp) pull-up resistance, $C_b[F]$: Communication line (SOp) load capacitance, $V_b[V]$: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10))
 - **4.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(10) Communication at different potential (1.8 V, 2.5 V) (simplified I^2C mode) (1/2)

(Ta = -40 to $+85^{\circ}$ C, 1.8 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

Parameter	Symbol	Conditions	HS	Note 1	LS	Note 2	LV	Note 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		1000 ^{Note 4}		300 ^{Note}		300 ^{Note}	kHz
		$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		400 ^{Note}		300 ^{Note}		300 ^{Note}	kHz
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note \ 5}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{split}$		300 ^{Note} 4		300 ^{Note} 4		300 ^{Note} 4	kHz
Hold time when SCLr = "L"	tLOW	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_{b} \leq 2.7 \ V, \\ C_{b} &= 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{split}$	475		1550		1550		ns
		$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	1150		1550		1550		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note 5}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k \Omega \end{split}$	1550		1550		1550		ns
Hold time when SCLr = "H"	tнісн	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	200		610		610		ns
		$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	600		610		610		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 5}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	610		610		610		ns

(Notes, Caution and Remarks are listed on the next page.)

(10) Communication at different potential (1.8 V, 2.5 V) (simplified I²C mode) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	HS ^t	Note 1	LS ^N	lote 2	LV ^N	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_{b} \leq 2.7 \ V, \\ C_{b} &= 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{split}$	1/f _{MCK} + 135 ^{Note}		1/f _{MCK} + 190 ^{Note 6}		1/f _{MCK} + 190 ^{Note} 6		ns
		$ 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega $	1/f _{MCK} + 190 ^{Note} 6		1/f _{MCK} + 190 ^{Note 6}		1/f _{MCK} + 190 ^{Note} 6		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note 5}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k \Omega \end{split}$	1/f _{MCK} + 190 ^{Note} 6		1/f _{MCK} + 190 ^{Note 6}		1/f _{MCK} + 190 ^{Note} 6		ns
Data hold time (transmission)	thd:dat	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_{b} \leq 2.7 \ V, \\ C_{b} &= 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{split}$	0	305	0	305	0	305	ns
		$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{C}_{\text{b}} = 100 \text{ pF}, \text{R}_{\text{b}} = 2.7 \text{ k}\Omega $	0	355	0	355	0	355	ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 5}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	0	405	0	405	0	405	ns

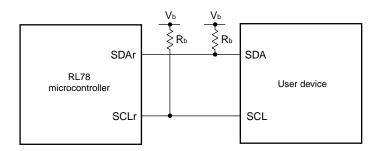
Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. The value must also be fclk/4 or lower.
- **5.** Use it with $EV_{DD0} \ge V_b$.
- 6. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".

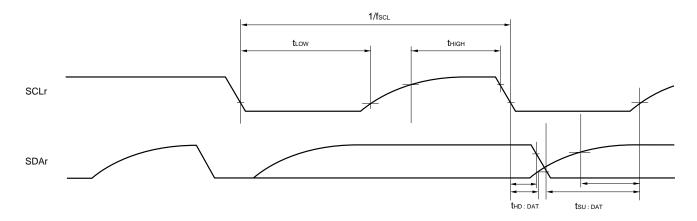
Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage
 - 2. r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
 n: Channel number (mn = 00, 02, 10)
 - **4.** IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.

2.5.2 Serial interface IICA

(1) I²C standard mode

(TA = -40 to +85°C, 1.6 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

Parameter	Symbol	Conditions		St	andard	Mode ^{No}	te 1		Unit
			HS	Note 2	LS ^N	lote 3	LV	lote 4	
			MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	2.7 V ≤ EV _{DD0} ≤ 3.6 V	0	100	0	100	0	100	kHz
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0	100	0	100	0	100	
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	0	100	0	100	0	100	
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	_		0	100	0	100	
Setup time of restart condition	tsu:sta	2.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	_		4.7		4.7		
Hold time ^{Note 5}	thd:STA	2.7 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-		4.0		4.0		
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-		4.7		4.7		
Hold time when SCLA0 = "H"	tніgн	2.7 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-		4.0		4.0		
Data setup time (reception)	tsu:dat	2.7 V ≤ EV _{DD0} ≤ 3.6 V	250		250		250		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	250		250		250		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	250		250		250		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-		250		250		
Data hold time (transmission) ^{Note 6}	thd:dat	2.7 V ≤ EV _{DD0} ≤ 3.6 V	0	3.45	0	3.45	0	3.45	μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0	3.45	0	3.45	0	3.45	
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	0	3.45	0	3.45	0	3.45	
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-	_	0	3.45	0	3.45	
Setup time of stop condition	tsu:sto	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	4.0		4.0		4.0		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.0		4.0		4.0		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	-		4.0		4.0		
Bus-free time	t _{BUF}	2.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.7 V ≤ EV _{DD0} ≤ 3.6 V	4.7		4.7		4.7		
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	_		4.7		4.7		

(Note and Remark are listed on the next page.)



(2) I²C fast mode, fast mode plus

(TA = -40 to +85°C, 1.6 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

Parameter	Symbol	Conditions			Fast M	ode ^{Note 7}				Mode Note 8	Unit
			HS	Note 2	LS'	Note 3	LV	lote 4	HS	Note 2	
			MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	2.7 V ≤ EV _{DD0} ≤ 3.6 V	0	400	0	400	0	400	0	1000	kHz
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0	400	0	400	0	400	-		
Setup time of restart	tsu:sta	2.7 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		0.26		μs
condition		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		-		
Hold time ^{Note 5}	thd:STA	2.7 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		0.26		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		-		
Hold time when SCLA0	tLow	2.7 V ≤ EV _{DD0} ≤ 3.6 V	1.3		1.3		1.3		0.5		μs
= "L"		1.8 V ≤ EV _{DD0} ≤ 3.6 V	1.3		1.3		1.3		-		
Hold time when SCLA0	t HIGH	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	0.6		0.6		0.6		0.26		μs
= "H"		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		-		
Data setup time	tsu:dat	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	100		100		100		50		ns
(reception)		1.8 V ≤ EV _{DD0} ≤ 3.6 V	100		100		100		_		
Data hold time	thd:dat	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	0	0.9	0	0.9	0	0.9	0	450	μs
(transmission)Note 6		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0	0.9	0	0.9	0	0.9	-		
Setup time of stop	tsu:sto	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	0.6		0.6		0.6		0.26		μs
condition		1.8 V ≤ EV _{DD0} ≤ 3.6 V	0.6		0.6		0.6		_		
Bus-free time	t BUF	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	1.3		1.3		1.3		0.5		μs
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	1.3		1.3		1.3		-		

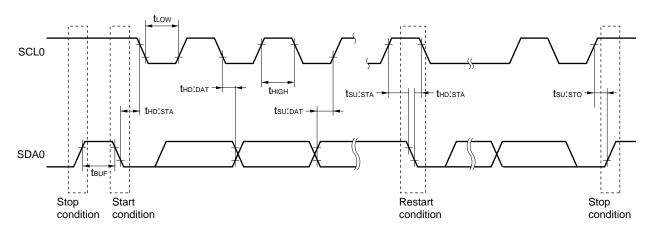
Notes 1. In normal mode, use it with fcLK \geq 1 MHz, 1.6 V \leq EVDD \leq 3.6 V.

- 2. HS is condition of HS (high-speed main) mode.
- 3. LS is condition of LS (low-speed main) mode.
- 4. LV is condition of LV (low-voltage main) mode.
- 5. The first clock pulse is generated after this period when the start/restart condition is detected.
- **6.** The maximum value (MAX.) of thd:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.
- 7. In fast mode, use it with fcLK \geq 3.5 MHz, 1.8 V \leq EVDD \leq 3.6 V.
- **8.** In fast mode plus, use it with fcLK \geq 10 MHz, 2.7 V \leq EVDD \leq 3.6 V.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

 $\label{eq:cb} \begin{array}{ll} \text{Standard mode:} & C_b = 400 \text{ pF, } R_b = 2.7 \text{ k}\Omega \\ \text{Fast mode:} & C_b = 320 \text{ pF, } R_b = 1.1 \text{ k}\Omega \\ \text{Fast mode plus:} & C_b = 120 \text{ pF, } R_b = 1.1 \text{ k}\Omega \end{array}$

IICA serial transfer timing



2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Division of A/D Converter Characteristics

Reference voltag	Reference voltage (+) = AV _{REFP} Reference voltage (-) = AV _{REFM}	Reference voltage (+) = AV _{DD} Reference voltage (-) = AV _{SS}	Reference voltage (+) = Internal refrence voltage Reference voltage (-) = AVss
High-accuracy channel; ANI0 to ANI12 (input buffer power supply: AVDD)	See 2.6.1 (1) See 2.6.1 (2)	See 2.6.1 (3)	See 2.6.1 (6)
Standard channel; ANI16 to ANI30 (input buffer power supply: V _{DD} or EV _{DD0})	See 2.6.1 (4)	See 2.6.1 (5)	
Temperature sensor, internal reference voltage output	See 2.6.1 (4)	See 2.6.1 (5)	-

- <R> (1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12
- <R> (T_A = -40 to +85°C, 2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V, AV_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (-) = AV_{REFM} = 0 V, HALT mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res				12	bit
Overall error ^{Notes 1, 2, 3}	AINL	12-bit resolution		±1.7	±3.3	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	3.375			μs
Zero-scale error ^{Notes 1, 2, 3}	Ezs	12-bit resolution		±1.3	±3.2	LSB
Full-scale errorNotes 1, 2, 3	Ers	12-bit resolution		±0.7	±2.9	LSB
Integral linearity errorNotes 1, 2, 3	ILE	12-bit resolution		±1.0	±1.4	LSB
Differential linearity errorNotes 1, 2, 3	DLE	12-bit resolution		±0.9	±1.2	LSB
Analog input voltage	VAIN		0		AVREFP	V

- **Notes 1.** TYP. Value is the average value at AV_{DD} = AV_{REFP} = 3 V and T_A = 25°C. MAX. value is the average value $\pm 3\sigma$ at normalized distribution.
 - 2. These values are the results of characteristic evaluation and are not checked for shipment.
 - 3. Excludes quantization error (±1/2 LSB).
- Cautions 1. Route the wiring so that noise will not be superimposed on each power line and ground line, and insert a capacitor to suppress noise.
 - In addition, separate the reference voltage line of AVREFP from the other power lines to keep it free from the influences of noise.
 - During A/D conversion, keep a pulse, such as a digital signal, that abruptly changes its level from being input to or output from the pins adjacent to the converter pins and P20 to P27 and P150 to P154.

<R> (2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

(TA = -40 to +85°C, 1.6 V \leq AVREFP \leq AVDD \leq VDD \leq 3.6 V, Vss = 0 V, AVss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8		12	bit
			$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8		10 ^{Note 1}	
			$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$		8 ^{Note 2}		
Overall error ^{Note 3}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±6.0	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±2.5	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	3.375			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	1.8 V ≤ AVREFP ≤ AVDD ≤ 3.6 V	6.75			
		ADTYP = 0, 8-bit resolution ^{Note 2}	1.6 V ≤ AVREFP ≤ AVDD ≤ 3.6 V	13.5			
		ADTYP = 1,	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	2.5625			
		8-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	5.125			
			$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	10.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±2.0	
Full-scale errorNote 3	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
		10-bit resolution	$1.8~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±4.5	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±2.0	
Integral linearity error Note 3	ILE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±1.5	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±1.0	
Differential linearity errorNote 3	DLE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±1.5	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±1.5	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±1.0	
Analog input voltage	Vain			0		AVREFP	٧

- Notes 1. Cannot be used for lower 2 bit of ADCR register
 - 2. Cannot be used for lower 4 bit of ADCR register
 - 3. Excludes quantization error (±1/2 LSB).

<R> (3) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI0 to ANI12

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V}, \text{AV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{DD}, \text{Reference voltage (-)} = \text{AV}_{SS} = 0 \text{ V})$

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$	8		12	bit
			1.8 V ≤ AV _{DD} ≤ 3.6 V	8		10 ^{Note 1}	
			1.6 V ≤ AV _{DD} ≤ 3.6 V		8 ^{Note 2}		
Overall error ^{Note 3}	AINL	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±7.5	LSB
		10-bit resolution	1.8 V ≤ AV _{DD} ≤ 3.6 V			±5.5	,
		8-bit resolution	1.6 V ≤ AV _{DD} ≤ 3.6 V			±3.0	,
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	3.375			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8~V \le AV_{DD} \le 3.6~V$	6.75			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6~V \le AV_{DD} \le 3.6~V$	13.5			
		ADTYP = 1,	2.4 V ≤ AV _{DD} ≤ 3.6 V	2.5625			
		8-bit resolution	1.8 V ≤ AV _{DD} ≤ 3.6 V	5.125			
			1.6 V ≤ AV _{DD} ≤ 3.6 V	10.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±6.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.5	
Full-scale error ^{Note 3}	E _F s	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±6.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.5	
Integral linearity errorNote 3	ILE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±3.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±2.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±1.5	
Differential linearity error ^{Note 3}	DLE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±2.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{DD} \leq 3.6 \text{ V}$			±1.5	
Analog input voltage	Vain			0		AV _{DD}	V

Notes 1. Cannot be used for lower 2 bit of ADCR register

- 2. Cannot be used for lower 4 bit of ADCR register
- **3.** Excludes quantization error ($\pm 1/2$ LSB).

<R> (4) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

(TA = -40 to +85°C, 1.6 V \leq EVDD0 \leq VDD \leq 3.6 V, 1.6 V \leq AVREFP \leq AVDD \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V, AVss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$	8		12	bit
			$1.8~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$	8		10 ^{Note 1}	
			$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$		8 ^{Note 2}		
Overall error ^{Note 3}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±7.0	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±5.5	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±3.0	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	4.125			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$	9.5			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$	57.5			
		ADTYP = 1,	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	3.3125			
		8-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	7.875			
			$1.6~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$	54.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±5.0	LSB
		10-bit resolution	$1.8~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±5.0	
		8-bit resolution	$1.6~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±2.5	
Full-scale errorNote 3	Ers	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±5.0	LSB
		10-bit resolution	$1.8~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±5.0	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±2.5	
Integral linearity errorNote 3	ILE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±3.0	LSB
		10-bit resolution	$1.8~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±2.0	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±1.5	
Differential linearity error Note 3	DLE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±2.0	
		8-bit resolution	$1.6~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±1.5	
Analog input voltage	VAIN			0		AV _{REFP} and EV _{DD0}	V
		Interanal reference voltage (2.4 V \leq V _{DD} \leq 3.6 V, HS (high-speed main) mode)			V _{BGR} Note 4		
		Temperature sensor (2.4 V \leq V _{DD} \leq 3.6 V,	V _{TMPS25} Note 4			V	

- Notes 1. Cannot be used for lower 2 bit of ADCR register
 - 2. Cannot be used for lower 4 bit of ADCR register
 - **3.** Excludes quantization error ($\pm 1/2$ LSB).
 - 4. See 2.6.2 Temperature sensor, internal reference voltage output characteristics.

<R> (5) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \ 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD0}} \le 3.6 \text{ V}, \ 1.6 \text{ V} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \ \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}, \ \text{AV}_{\text{SS}} = 0 \text{ V}, \ \text{Reference voltage (+)} = \text{AV}_{\text{DD}}, \ \text{Reference voltage (-)} = \text{AV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit	
Resolution	Res		2.4 V ≤ AV _{DD} ≤ 3.6 V	8		12	bit	
			1.8 V ≤ AV _{DD} ≤ 3.6 V	8		10 ^{Note 1}		
			1.6 V ≤ AV _{DD} ≤ 3.6 V		8 ^{Note 2}			
Overall error ^{Note 3}	AINL	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±8.5	LSB	
		10-bit resolution	1.8 V ≤ AV _{DD} ≤ 3.6 V			±6.0	•	
		8-bit resolution	1.6 V ≤ AV _{DD} ≤ 3.6 V			±3.5	•	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V	4.125			μs	
		ADTYP = 0, 10-bit resolution ^{Note 1}	1.8 V ≤ AV _{DD} ≤ 3.6 V	9.5				
		ADTYP = 0, 8-bit resolution ^{Note 2}	1.6 V ≤ AV _{DD} ≤ 3.6 V	57.5				
		ADTYP = 1,	2.4 V ≤ AV _{DD} ≤ 3.6 V	3.3125			μs	
		8-bit resolution	1.8 V ≤ AV _{DD} ≤ 3.6 V	7.875				
			$1.6~V \le AV_{DD} \le 3.6~V$	54.25				
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±8.0	LSB	
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.5		
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±3.0		
Full-scale errorNote 3	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±8.0	LSB	
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±5.5		
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±3.0		
Integral linearity errorNote 3	ILE	12-bit resolution	$2.4~V \le AV_{DD} \le 3.6~V$			±3.5	LSB	
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±2.5		
		8-bit resolution	1.6 V ≤ AV _{DD} ≤ 3.6 V			±1.5		
Differential linearity error ^{Note 3}	DLE	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±2.5	LSB	
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			±2.5		
		8-bit resolution	1.6 V ≤ AV _{DD} ≤ 3.6 V			±2.0		
Analog input voltage	VAIN			0		AV _{DD} and EV _{DD0}	V	
		Interanal reference voltage $(2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}, \text{ HS (high-speed main) mode)}$		V _{BGR} Note 4			V	
	Temperature sensor output voltage (2.4 V ≤ V _{DD} ≤ 3.6 V, HS (high-speed main) mode)				V _{TMPS25} Note 4			

- Notes 1. Cannot be used for lower 2 bit of ADCR register
 - 2. Cannot be used for lower 4 bit of ADCR register
 - 3. Excludes quantization error (±1/2 LSB).
 - 4. See 2.6.2 Temperature sensor, internal reference voltage output characteristics.

<R> (6) When reference voltage (+) = Internal reference voltage (1.45 V) (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVss (ADREFM = 0), target ANI pin: ANI0 to ANI12, ANI16 to ANI30

(TA = -40 to $+85^{\circ}$ C, 2.4 V \leq VDD \leq 3.6 V, 1.6 V \leq EVDD \leq VDD, 1.6 V \leq AVDD \leq VDD, Vss = EVSSO = 0 V, AVSS = 0 V, Reference voltage (+) = Internal reference voltage, Reference voltage (-) = AVSS = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		bit
Conversion time	tconv	8-bit resolution	16			μs
Zero-scale error ^{Note}	Ezs	8-bit resolution			±4.0	LSB
Integral linearity error Note	ILE	8-bit resolution			±2.0	LSB
Differential linearity error ^{Note}	DLE	8-bit resolution			±2.5	LSB
Reference voltage (+)	AV _{REF(+)}	= Internal reference voltage (V _{BGR})	1.38	1.45	1.5	V
Analog input voltage	VAIN		0		V _{BGR}	٧

Note Excludes quantization error (±1/2 LSB).

2.6.2 Temperature sensor, internal reference voltage output characteristics

(TA = -40 to +85°C, 2.4 V \leq VDD \leq 3.6 V, Vss = 0 V, HS (high-speed main) mode)

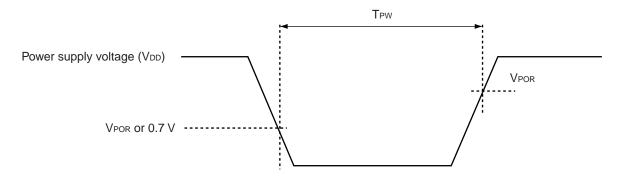
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V _{TMPS25}	Setting ADS register = 80H, T _A = +25°C		1.05		V
Internal reference voltage	V _{BGR}	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	Fvтмps	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		10			μs

2.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	Vpor	Power supply rise time		1.51	1.55	V
	V _{PDR}	Power supply fall time	1.46	1.50	1.54	V
Minimum pulse widthNote	Tpw		300			μs

Note This is the time required for the POR circuit to execute a reset when V_{DD} falls below V_{PDR}. When the microcontroller enters STOP mode or if the main system clock (f_{MAIN}) has been stopped by setting bit 0 (HIOSTOP) and bit 7 (MSTOP) of the clock operation status control register (CSC), this is the time required for the POR circuit to execute a reset before V_{DD} rises to V_{POR} after having fallen below 0.7 V.





2.6.4 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	V _{LVD2}	Power supply rise time	3.07	3.13	3.19	V
voltage			Power supply fall time	3.00	3.06	3.12	V
		V _{LVD3}	Power supply rise time	2.96	3.02	3.08	V
			Power supply fall time	2.90	2.96	3.02	V
		V _{LVD4}	Power supply rise time	2.86	2.92	2.97	V
			Power supply fall time	2.80	2.86	2.91	V
		V _{LVD5}	Power supply rise time	2.76	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
		V _{LVD6}	Power supply rise time	2.66	2.71	2.76	V
			Power supply fall time	2.60	2.65	2.70	V
		V _{LVD7}	Power supply rise time	2.56	2.61	2.66	V
			Power supply fall time	2.50	2.55	2.60	V
		V _{LVD8}	Power supply rise time	2.45	2.50	2.55	V
			Power supply fall time	2.40	2.45	2.50	V
		V _{LVD9}	Power supply rise time	2.05	2.09	2.13	V
			Power supply fall time	2.00	2.04	2.08	V
		V _{LVD10}	Power supply rise time	1.94	1.98	2.02	V
			Power supply fall time	1.90	1.94	1.98	V
		V _{LVD11}	Power supply rise time	1.84	1.88	1.91	V
			Power supply fall time	1.80	1.84	1.87	V
		V _{LVD12}	Power supply rise time	1.74	1.77	1.81	V
			Power supply fall time	1.70	1.73	1.77	V
		V _{LVD13}	Power supply rise time	1.64	1.67	1.70	V
			Power supply fall time	1.60	1.63	1.66	V
Minimum pu	lse width	t _L w		300			μs
Detection de	elay time					300	μs

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: VDD = 2.7 to 3.6 V@1 MHz to 32 MHz

 V_{DD} = 2.4 to 3.6 V@1 MHz to 16 MHz

LS (low-speed main) mode: V_{DD} = 1.8 to 3.6 V@1 MHz to 8 MHz LV (low-voltage main) mode: V_{DD} = 1.6 to 3.6 V@1 MHz to 4 MHz

LVD Detection Voltage of Interrupt & Reset Mode $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
Interrupt & reset	V _{LVD13}	VPOC2, VPOC1, VPOC0 = 0, 0, 0, falling reset voltage			1.63	1.66	V
mode	V _{LVD12}	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
			Falling interrupt voltage	1.70	1.73	1.77	V
	VLVD11	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	٧
			Falling interrupt voltage	1.80	1.84	1.87	>
	V _{LVD4}	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	>
			Falling interrupt voltage	2.80	2.86	2.91	V
	V _{LVD11}	VPOC2, VPOC1, VPOC0 =	0, 0, 1, falling reset voltage	1.80	1.84	1.87	>
	VLVD10	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	>
VLVD9 VLVD2			Falling interrupt voltage	1.90	1.94	1.98	>
	V _{LVD9}	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
			Falling interrupt voltage	2.00	2.04	2.08	V
	V _{LVD2}	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	>
			Falling interrupt voltage	3.00	3.06	3.12	V
	V _{LVD8}	VPOC2, VPOC1, VPOC0 =	2.40	2.45	2.50	V	
	V _{LVD7}	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	>
			Falling interrupt voltage	2.50	2.55	2.60	V
	V _{LVD6}	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	٧
			Falling interrupt voltage	2.60	2.65	2.70	V
	V _{LVD5}	VPOC2, VPOC1, VPOC0 =	VPOC2, VPOC1, VPOC0 = 0, 1, 1, falling reset voltage		2.75	2.81	V
\	V _{LVD4}	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
			Falling interrupt voltage	2.80	2.86	2.91	V
	V _{LVD3}	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
			Falling interrupt voltage	2.90	2.96	3.02	V

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: VDD = 2.7 to 3.6 V@1 MHz to 32 MHz

V_{DD} = 2.4 to 3.6 V@1 MHz to 16 MHz

LS (low-speed main) mode: V_{DD} = 1.8 to 3.6 V@1 MHz to 8 MHz LV (low-voltage main) mode: V_{DD} = 1.6 to 3.6 V@1 MHz to 4 MHz

2.6.5 Supply voltage rise slope characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SV _{DD}				54	V/ms

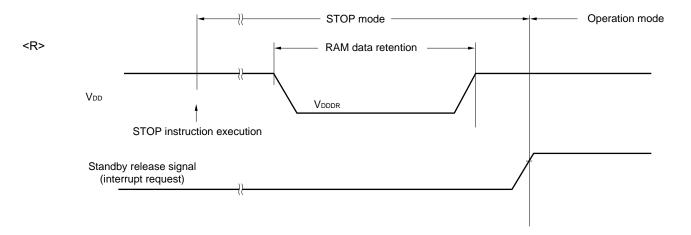
Caution Be sure to maintain the internal reset state until V_{DD} reaches the operating voltage range specified in 2.4 AC Characteristics, by using the LVD circuit or external reset pin.

<R> 2.7 RAM Data Retention Characteristics

< R > (TA = -40 to +85°C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 ^{Note}		3.6	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



<R> 2.8 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclk	1.8 V ≤ V _{DD} ≤ 3.6 V	1		32	MHz
Number of code flash rewrites ^{Notes 1, 2}	Cerwr	Retained for 20 years TA = 85°C ^{Note 3}	1,000			Times
Number of data flash rewrites ^{Notes 1, 2}		Retained for 1 years TA = 25°C ^{Note 3}		1,000,000		
		Retained for 5 years TA = 85°C ^{Note 3}	100,000			
		Retained for 20 years TA = 85°C ^{Note 3}	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

2.9 Dedicated Flash Memory Programmer Communication (UART)

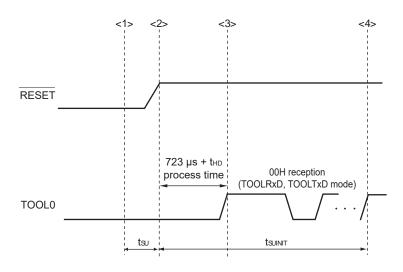
$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115.2 k		1 M	bps

2.10 Timing Specs for Switching Flash Memory Programming Modes

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	How long from when an external reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the external reset ends.			100	ms
	How long from when the TOOL0 pin is placed at the low level until a external reset ends	tsu	POR and LVD reset must end before the external reset ends.	10			μs
<r></r>	How long the TOOL0 pin must be kept at the low level after an external reset ends (except flash firmware processing time)	tно	POR and LVD reset must end before the external reset ends.	1			ms



<R>

- <1> The low level is input to the TOOL0 pin.
- <2> The pins reset ends (POR and LVD reset must end before the external reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

 t_{SU} : How long from when the TOOL0 pin is placed at the low level until a external reset ends

<R> thd: How long to keep the TOOL0 pin at the low level from when the external resets end (except flash firmware processing time)

3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40 \text{ to } +105^{\circ}\text{C}$)

This chapter describes the following electrical specifications.

Target products G: Industrial applications T_A = -40 to +105°C
R5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNA
R5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFB
R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA
R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB

- Cautions 1. The RL78/G1A has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EV_{DD0} or EVss₀ pin, replace EV_{DD0} with V_{DD}, or replace EVss₀ with Vss.
 - 3. Please contact Renesas Electronics sales office for derating of operation under T_A = +85°C to +105°C. Derating is the systematic reduction of load for the sake of improved reliability.

Remark When RL78/G1A is used in the range of $T_A = -40$ to +85°C, see 2. **ELECTRICAL SPECIFICATIONS** ($T_A = -40$ to +85°C).



3.1 Absolute Maximum Ratings

Absolute Maximum Ratings ($T_A = 25^{\circ}C$) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.5 to +6.5	V
	EV _{DD0}		-0.5 to +6.5	V
	AVDD		-0.5 to +4.6	V
	AVREFP		-0.3 to AV _{DD} +0.3 ^{Note 3}	V
	EVsso		-0.5 to +0.3	٧
	AVss		-0.5 to +0.3	V
	AVREFM		-0.3 to AV _{DD} +0.3 ^{Note 3} and AV _{REFM} ≤ AV _{REFP}	V
REGC pin input voltage	Virego	REGC	-0.3 to +2.8 and -0.3 to V _{DD} +0.3 ^{Note 1}	V
Input voltage	VI1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	-0.3 to EV _{DD0} +0.3 and -0.3 to V _{DD} +0.3 ^{Note 2}	V
	V _{I2}	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} +0.3 ^{Note 2}	V
	V _{I4}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Output voltage	V ₀₁	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	-0.3 to EV _{DD0} +0.3 ^{Note 2}	V
	V _{O2}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Analog input voltage	V _{Al1}	ANI16 to ANI30	-0.3 to EV _{DD0} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	V
	V _{AI2}	ANI0 to ANI12	-0.3 to AV _{DD} +0.3 and -0.3 to AV _{REF(+)} +0.3 $^{\text{Notes 2, 4}}$	V

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
 - 2. Must be 6.5 V or lower.
 - 3. Must be 4.6 V or lower.
 - **4.** Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - 2. AV_{REF(+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage

Absolute Maximum Ratings ($T_A = 25$ °C) (2/2)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	-40	mA
		Total of all pins –170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	-70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P70 to P77,	-100	mA
	Iон ₂	Per pin	P20 to P27, P150 to P154	-0.1	mA
		Total of all pins		-1.3	mA
Output current, low			P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	40	mA
		Total of all pins 170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P60 to P63, P70 to P77	100	mA
	lo _{L2}	Per pin	P20 to P27, P150 to P154	0.4	mA
		Total of all pins		6.4	mA
Operating ambient	TA	In normal operati	on mode	-40 to +105	°C
temperature		In flash memory p	programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

3.2 Oscillator Characteristics

3.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/crystal resonator	$2.7~\text{V} \leq \text{V}_{\text{DD}} \leq 3.6~\text{V}$	1.0		20.0	MHz
frequency (fx) ^{Note}		$2.4~\textrm{V} \leq \textrm{V}_\textrm{DD} < 2.7~\textrm{V}$	1.0		16.0	
XT1 clock oscillation frequency (fx) ^{Note}	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. See AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

<R> Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

3.2.2 On-chip oscillator characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

(1A 40 to 100 0, 2.4 t 2 tbb 2 0.0 t, too 0 t)							
Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator oscillation frequency Notes 1, 2	fін			1		32	MHz
High-speed on-chip oscillator		+85 to +105 °C	$2.4~V \leq V_{DD} \leq 3.6~V$	-2		+2	%
oscillation frequency accuracy		–20 to +85 °C	$2.4~V \leq V_{DD} \leq 3.6~V$	-1		+1	%
		–40 to −20 °C	$2.4~V \le V_{DD} \le 3.6~V$	-1.5		+1.5	%
Low-speed on-chip oscillator oscillation frequency	fıL				15		kHz
Low-speed on-chip oscillator oscillation frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of HOCODIV register.
 - **2.** This indicates the oscillator characteristics only. See AC Characteristics for instruction execution time.

3.3 DC Characteristics

3.3.1 Pin characteristics

<R> (TA = -40 to +105°C, 2.4 V \le AVDD \le VDD \le 3.6 V, 2.4 V \le EVDD0 \le VDD \le 3.6 V, Vss = EVss0 = 0 V) (1/5)

Items	Symbol	Conditions	Conditions				Unit
Output current, high ^{Note 1}	Іон1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	$2.4~\text{V} \le \text{EV}_{\text{DD0}} \le 3.6~\text{V}$			-3.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			-10.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			-5.0	mA
		Total of P05, P06, P10 to P16, P30,	$2.7~V \le EV_{DD0} \le 3.6~V$			-19.0	mA
		P31, P50, P51, P70 to P77, (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			-10.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} ≤ 3.6 V			-29.0	mA
	І он2	Per pin for P20 to P27, P150 to P154	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			-0.1 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	2.4 V ≤ AV _{DD} ≤ 3.6 V			-1.3	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DDO}, V_{DD} pins to an output pin.
 - 2. However, do not exceed the total current value.
 - 3. Specification under conditions where the duty factor ≤ 70%.
 The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = (IoH × 0.7)/(n × 0.01)
 <Example> Where n = 80% and IoH = -10.0 mA
 Total output current of pins = (-10.0 × 0.7)/(80 × 0.01) ≅ -8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.

<R> (T_A = −40 to +105°C, 2.4 V ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V) (2/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	lo _{L1}	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141				8.5 ^{Note 2}	mA
		Per pin for P60 to P63				15.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			15.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			9.0	mA
		Total of P05, P06, P10 to P16, P30,	$2.7~V \le EV_{DD0} \le 3.6~V$			35.0	mA
		P31, P50, P51, P60 to P63, P70 to P77 (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			20.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				50.0	mA
	Per pin for P20 to P27, P150 to P154 Total of all pins (When duty $\leq 70\%$ Note 3)					0.4 ^{Note 2}	mA
			$2.4 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			5.2	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVsso and Vss pin.
 - 2. However, do not exceed the total current value.
 - 3. Specification under conditions where the duty factor ≤ 70%.
 The output current value that has changed to the dury factor > 70% the duty ratio can can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = (IoL × 0.7)/(n × 0.01)
 <Example> Where n = 80% and IoL = 10.0 mA
 Total output current of pins = (10.0 × 0.7)/(80 × 0.01) ≅ 8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$ (3/5)

(1A +0 t0 · 10	O O, Z V	3 A V D D 3 V D D 3 3.0 V, Z.7 V 3 E V D	DO 3 VDD 3 0.0 V, V33 -	- V 000 V	, •,		(3/3
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V _{IH1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Normal input buffer	0.8EVDD0		EV _{DD0}	V
	V _{IH2} P01, P03, P04, P10, P11, P13 to P16, P43		TTL input buffer $3.3 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	2.0		EV _{DD0}	V
			TTL input buffer 2.4 V ≤ EV _{DD0} < 3.3 V	1.5		EV _{DD0}	V
	VIH3	P20 to P27, P150 to P154	0.7AV _{DD}		AVDD	V	
	V _{IH4}	P60 to P63	0.7EV _{DD0}		6.0	V	
	V _{IH5}	P121 to P124, P137, EXCLK, EXCLK	0.8V _{DD}		V _{DD}	V	
Input voltage, low	VIL1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Normal input buffer	0		0.2EV _{DD0}	V
	V _{IL2}	P01, P03, P04, P10, P11, P13 to P16, P43	TTL input buffer 3.3 V ≤ EVDD0 ≤ 3.6 V	0		0.5	V
			TTL input buffer 2.4 V ≤ EV _{DD0} < 3.3 V			0.32	V
	V _{IL3}	P20 to P27, P150 to P154	0		0.3AV _{DD}	V	
	V _{IL4}	P60 to P63		0		0.3EV _{DD0}	V
	VIL5	P121 to P124, P137, EXCLK, EXCLK	(S, RESET	0		0.2V _{DD}	V

Caution The maximum value of V_{IH} of pins P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 is EV_{DD0}, even in the N-ch open-drain mode.

low

 V_{OL2}

 V_{OL3}

Items Symbol TYP. MAX. Unit Conditions MIN. $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ Output voltage, P00 to P06, P10 to P16, P30, P31, EV_{DD0} -V_{OH1} V P40 to P43, P50, P51, P70 to P77, $I_{OH1} = -2.0 \text{ mA}$ high 0.6 P120, P130, P140, P141 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ EV_{DD0} -٧ $I_{OH1} = -1.5 \text{ mA}$ 0.5 $2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V},$ V_{OH2} P20 to P27, P150 to P154 AV_{DD} -V $I_{OH2} = -100 \mu A$ 0.5 Output voltage, V_{OL1} P00 to P06, P10 to P16, P30, P31, $2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ 0.6 V

 $I_{OL1} = 3.0 \text{ mA}$

 $I_{OL1} = 1.5 \text{ mA}$

 $I_{OL1} = 0.6 \text{ mA}$

 $I_{OL2} = 400 \mu A$

 $I_{OL3} = 3.0 \text{ mA}$

I_{OL3} = 2.0 mA

 $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$

 $2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$

 $2.4 \text{ V} \le AV_{DD} \le 3.6 \text{ V},$

 $2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$

 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

P40 to P43, P50, P51, P70 to P77,

P120, P130, P140, P141

P20 to P27, P150 to P154

P60 to P63

Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(4/5)

0.4

0.4

0.4

0.4

0.4

V

V

V

V

٧

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$ (5/5)

Items	Symbol	Condition	Conditions			TYP.	MAX.	Unit
Input leakage current, high	Ішн1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P140, P141	V _I = EV _{DD0}				1	μΑ
	I _{LIH2} P137, RESET V _I = V _{DD}				1	μΑ		
	Ішнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	(X1, X2, XT1, XT2, EXCLK, exte				1	μΑ
				In resonator connection			10	μΑ
	ILIH4	P20 to P27, P150 to P154	V _I = AV _{DD}				1	μΑ
Input leakage current, low	ILIL1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P67, P70 to P77, P120, P140, P141	V _I = EV _{SS0}				-1	μА
	ILIL2	P137, RESET	Vı = Vss				-1	μΑ
	Ішз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	Vı = Vss	In input port or external clock input			-1	μΑ
				In resonator connection			-10	μΑ
	ILIL4	P20 to P27, P150 to P154	Vı = AVss				-1	μΑ
On-chip pull-up resistance	Ru	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	V ₁ = EVss ₀ , In input port		10	20	100	kΩ

3.3.2 Supply current characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

(1/3)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply current	I _{DD1} Note 1	Operating mode	HS (high-speed main) mode ^{Note 5}	f _{IH} = 32 MHz ^{Note 3}	Basic operation	V _{DD} = 3.0 V		2.1		mA
					Normal operation	V _{DD} = 3.0 V		4.6	7.5	mA
				f _{IH} = 24 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		3.7	5.8	mA
				f _{IH} = 16 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		2.7	4.2	mA
			HS (high-speed main) mode ^{Note 5}	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$	Normal operation	Square wave input		3.0	4.9	mA
						Resonator connection		3.2	5.0	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$	Normal operation	Square wave input		1.9	2.9	mA
						Resonator connection		1.9	2.9	
			Subsystem clock mode	f _{SUB} = 32.768 kHz ^{Note 4} T _A = -40°C	Normal operation	Square wave input		4.1	4.9	μA
						Resonator connection		4.2	5.0	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +25°C	Normal operation	Square wave input		4.2	4.9	μΑ
						Resonator connection		4.3	5.0	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +50°C	Normal operation	Square wave input		4.3	5.5	μA
						Resonator connection		4.4	5.6	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +70°C	Normal operation	Square wave input		4.5	6.3	μΑ
						Resonator connection		4.6	6.4	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +85°C	Normal operation	Square wave input		4.8	7.7	μΑ
						Resonator connection		4.9	7.8	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +105°C	Normal operation	Square wave input		6.9	19.7	μА
						Resonator connection		7.0	19.8	

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDDO, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDDO or Vss, EVsso. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, on-chip pull-up/pull-down resistors, and data flash rewriting.
 - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 3. When high-speed system clock and subsystem clock are stopped.
 - **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1). Not including the current flowing into the RTC, 12-bit interval timer and watchdog timer
 - **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: V_{DD} = 2.7 V to 3.6 V@1 MHz to 32 MHz V_{DD} = 2.4 V to 3.6 V@1 MHz to 16 MHz

- **Remarks 1.** fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$ (2/3)

Parameter	Symbol	, • <u>-</u> -		V, V ss = EV sso = $0 VConditions$		MIN.	TYP.	MAX.	(2/3) Unit
Supply	I _{DD2} Note 2	HALT	HS (high-speed	f _{IH} = 32 MHz ^{Note 4}	V _{DD} = 3.0 V		0.54	2.90	mA
current ^{Note 1}		mode	main) mode ^{Note 7}	f _{IH} = 24 MHz ^{Note 4}	V _{DD} = 3.0 V		0.44	2.30	mA
				f _{IH} = 16 MHz ^{Note 4}	V _{DD} = 3.0 V		0.40	1.70	mA
			HS (high-speed	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.90	mA
			main) mode ^{Note 7}	$V_{DD} = 3.0 \text{ V}$	Resonator connection		0.45	2.00	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	1.02	mA
				$V_{DD} = 3.0 \text{ V}$	Resonator connection		0.26	1.10	
			Subsystem clock	f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.25	0.57	μΑ
		m	mode	T _A = -40°C	Resonator connection		0.44	0.76	
				f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.30	0.57	μΑ
				T _A = +25°C	Resonator connection		0.49	0.76	
				f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.38	1.17	μΑ
				T _A = +50°C	Resonator connection		0.57	1.36	
				fsuB = 32.768 kHz ^{Note 5}	Square wave input		0.52	1.97	μΑ
				T _A = +70°C	Resonator connection		0.71	2.16	
				f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.97	3.37	μΑ
				T _A = +85°C	Resonator connection		1.16	3.56	
				f _{SUB} = 32.768 kHz ^{Note 5} T _A = +105°C	Square wave input		3.01	15.37	μΑ
				1A - +105 C	Resonator connection		3.20	15.56	
	I _{DD3} Note 6	STOP	T _A = -40°C				0.16	0.50	μΑ
		mode ^{Note 8}	T _A = +25°C				0.23	0.50	
			T _A = +50°C				0.34	1.10	
			T _A = +70°C				0.46	1.90	
			T _A = +85°C			0.75	3.30		
			T _A = +105°C				2.94	15.30	

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD and EVDDO, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDDO or Vss, EVsso. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, on-chip pull-up/pull-down resistors, and data flash rewriting.
 - 2. During HALT instruction execution by flash memory.
 - 3. When high-speed on-chip oscillator and subsystem clock are stopped.
 - 4. When high-speed system clock and subsystem clock are stopped.
 - **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). Including the current flowing into the RTC. However, not including the current flowing into the 12-bit interval timer, and watchdog timer.
 - **6.** When subsystem clock is stopped. Not including the current flowing into the RTC, 12-bit interval timer, watchdog timer.
 - **7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V} @1 \text{ MHz to } 32 \text{ MHz}$ $2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V} @1 \text{ MHz to } 16 \text{ MHz}$

- **8.** Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - **4.** Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is $T_A = 25^{\circ}C$

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$ (3/3)

(1A = -40 to +105 t	C, 2.4 V > EVL	0.0 Z VUU Z 3.0 V	, VSS - EVSS0 - U V)				(3/3)
Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	_{FIL} Note 1				0.20		μΑ
RTC operating current	IRTC Notes 1, 2, 3				0.02		μΑ
12-bit interval timer operating current					0.02		μΑ
Watchdog timer operating current	_{WDT} Notes 1, 2, 5	fı∟ = 15 kHz			0.22		μΑ
A/D converter operating current	ADC Notes 6, 7	AV _{DD} = 3.0 V, W	hen conversion at maximum speed		420	720	μА
AV _{REF(+)} current	IAVREF Note 8	AV _{DD} = 3.0 V, A[DREFP1 = 0, ADREFP0 = 0 ^{Note 7}		14.0	25.0	μΑ
		AV _{REFP} = 3.0 V, A	ADREFP1 = 0, ADREFP0 = 1 ^{Note 10}		14.0	25.0	μА
		ADREFP1 = 1, A	DREFP0 = 0 ^{Note 1}		14.0	25.0	μΑ
A/D converter reference voltage current	ADREF Notes 1, 9	V _{DD} = 3.0 V			75.0		μА
Temperature sensor operating current	I _{TMPS} Note 1	V _{DD} = 3.0 V			75.0		μА
LVD operating current	I _{LVD} Notes 1, 11				0.08		μΑ
BGO operating current	I _{BGO} Notes 1, 12				2.5	12.2	mA
Self-programming operating current	FSP ^{Notes 1, 13}				2.5	12.2	mA
SNOOZE operating	Isnoz	A/D converter	The mode is performed ^{Notes 1, 14}		0.50	1.10	mA
current	operation		During A/D conversion ^{Note 1}		0.60	1.34	mA
		$(AV_{DD} = 3.0 \text{ V})$	During A/D conversionNote 7		420	720	μΑ
		CSI/UART opera	ation ^{Note 1}		0.70	1.54	mA

(Notes and Remarks are listed on the next page.)

<R> Notes 1. Current flowing to VDD.

- 2. When high-speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- **5.** Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2, or IDD3 and IWDT when the watchdog timer is in operation.
- **6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC, IAVREF, IADREF when the A/D converter operates in an operation mode or the HALT mode.
- 7. Current flowing to the AVDD.
- 8. Current flowing from the reference voltage source of A/D converter.
- 9. Operation current flowing to the internal reference voltage.
- 10. Current flowing to the AVREFP.
- **11.** Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
- 12. Current flowing only during data flash rewrite.
- 13. Current flowing only during self programming.
- Remarks 1. fil.: Low-speed on-chip oscillator clock frequency
 - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 3. fclk: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is TA = 25°C

3.4 AC Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \ AV_{DD} \leq V_{DD} \leq 3.6 \ \text{V}, \ 2.4 \ \text{V} \leq EV_{DD0} \leq V_{DD} \leq 3.6 \ \text{V}, \ V_{SS} = EV_{SS0} = 0 \ \text{V})$

Items	Symbol		Condition	5	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Tcy	Main system	HS (high-speed	$2.7 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}$	0.03125		1	μs
instruction execution time)		clock (fmain) operation	main) mode	2.4 V ≤ V _{DD} < 2.7 V	0.0625		1	μs
		Subsystem clo	ock (fsuB)	$2.4 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	28.5	30.5	31.3	μs
		In the self .	HS (high-speed	2.7 V ≤ V _{DD} ≤ 3.6 V	0.03125		1	μs
		programming mode	main) mode	2.4 V ≤ V _{DD} < 2.7 V	0.0625		1	μs
External system clock	fex	$2.7 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}$		1.0		20.0	MHz	
frequency		$2.4 \text{ V} \leq V_{DD} <$	2.7 V		1.0		16.0	MHz
	fexs				32		35	kHz
External system clock input	texh, texl	2.7 V ≤ V _{DD} ≤ 3.6 V						ns
high-level width, low-level width		$2.4 \text{ V} \le \text{V}_{DD} \le 2.7 \text{ V}$			30			ns
width	texhs, texhs				13.7			μs
TI00, TI01, TI03 to TI07 input high-level width, low-level width	tтін, tтіL				1/fмск+10			ns ^{Note}
TO00, TO01, TO03 to	f то	HS (high-spee	ed main) 2.7	V ≤ EV _{DD0} ≤ 3.6 V			8	MHz
TO07 output frequency		mode	2.4	V ≤ EV _{DD0} < 2.7 V			4	MHz
PCLBUZ0, PCLBUZ1	f PCL	HS (high-spee	ed main) 2.7	V ≤ EV _{DD0} ≤ 3.6 V			8	MHz
output frequency		mode	2.4	V ≤ EV _{DD0} < 2.7 V			4	MHz
Interrupt input high-level	tinth, tintl	INTP0	2.4	$V \le V_{DD} \le 3.6 \text{ V}$	1			μs
width, low-level width		INTP1 to INTE	2.4	V ≤ EV _{DD0} ≤ 3.6 V	1			μs
Key interrupt input high-level width, low-level width	tkr	KR0 to KR9		$V \le EV_{DD0} \le 3.6 V$, $V \le AV_{DD0} \le 3.6 V$	250			ns
RESET low-level width	trsl		<u>.</u>		10			μs

Note The following conditions are required for low-voltage interface when EV_{DD0} < V_{DD}.

 $2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MIN. 125 ns

Nov 30, 2016

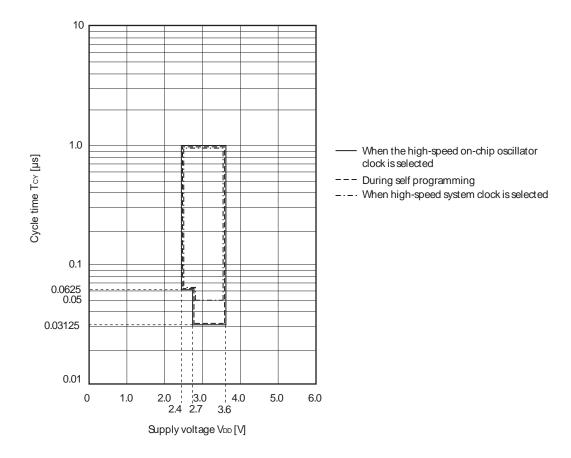
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer clock select register 0 (TPS0) and timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation

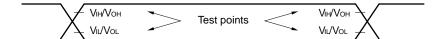
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Tcy vs VDD (HS (high-speed main) mode)

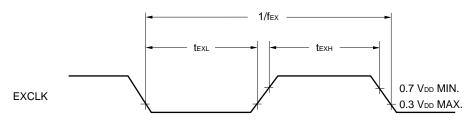


AC Timing Test Points

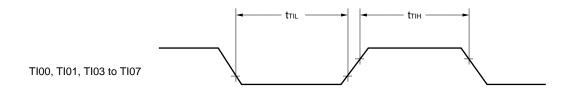


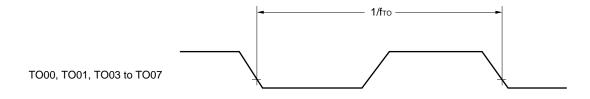


External System Clock Timing

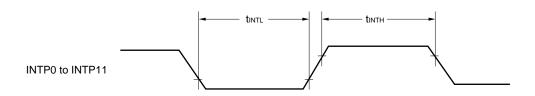


<R> TI/TO Timing

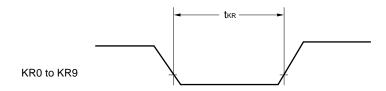




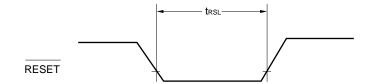
Interrupt Request Input Timing



Key Interrupt Input Timing



RESET Input Timing



3.5 Peripheral Functions Characteristics

AC Timing Test Points



<R>



3.5.1 Serial array unit

(1) During communication at same potential (UART mode) (dedicated baud rate generator output) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate ^{Note 1}					fмск/12	bps
		Theoretical value of the maximum transfer rate fclk = 32 MHz, fmck = fclk			2.6 ^{Note 2}	Mbps

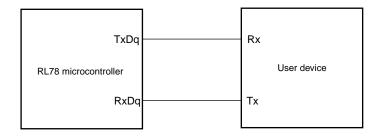
Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.

2. The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$.

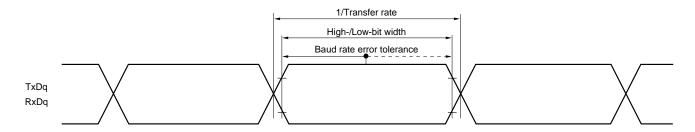
 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MAX. 1.3 Mbps

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

fmck: Serial array unit operation clock frequency(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,n: Channel number (mn = 00 to 03, 10, 11))

(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Parameter	Symbol	Condition	Conditions		TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	tkcy1 ≥ 4/fcLk	250			ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fcLk	500			ns
SCKp high-/low-level width	tĸнı,	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		tkcy1/2 - 36			ns
	t _{KL1}	$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		tkcy1/2 - 76			ns
SIp setup time (to SCKp↑)Note 1	tsıĸ1	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		66			ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		113			ns
SIp hold time (from SCKp↑) ^{Note 1}	t _{KSI1}			38			ns
Delay time from SCKp↓ to SOp output ^{Note 2}	tkso1	C = 30 p ^{Note 3}				50	ns

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)

<R> (3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input) (T_A = −40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, Vss = EV_{SS0} = 0 V)

Parameter	Symbol	Cond	ditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time ^{Note 1}	tkcy2	2.7 V ≤ EV _{DD0} ≤ 3.6 V	16 MHz < f _{MCK}	16/fмск			ns
			fмcк ≤ 16 MHz	12/fмск			ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V		12/fмск and 1000			ns
SCKp high-/low-level width	t _{KH2} ,	2.7 V ≤ EV _{DD0} ≤ 3.6 V	2.7 V ≤ EV _{DD0} ≤ 3.6 V				ns
	t _{KL2}	2.4 V ≤ EV _{DD0} ≤ 3.6 V		tkcy2/2-16			ns
Slp setup time	tsik2	2.7 V ≤ EV _{DD0} ≤ 3.6 V	,	1/f _{MCK} + 40			ns
(to SCKp↑)Note 2		2.4 V ≤ EV _{DD0} ≤ 3.6 V	,	1/fmck + 60			ns
Slp hold time	t _{KSI2}	2.7 V ≤ EV _{DD0} ≤ 3.6 V	,	1/fмск+62			ns
(from SCKp↑) ^{Note 2}		2.4 V ≤ EV _{DD0} ≤ 3.6 V		1/fмск+62			ns
Delay time from SCKp↓ to	tkso2	C = 30 pF ^{Note 4}	$2.7~V \le EV_{DD0} \le 3.6~V$			2/fмск+66	ns
SOp output ^{Note 3}			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			2/fмск+113	ns

- Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SOp output lines.

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3),

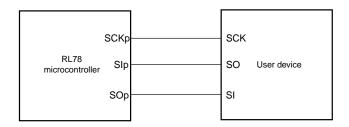
g: PIM number (g = 0, 1)

2. fmck: Serial array unit operation clock frequency

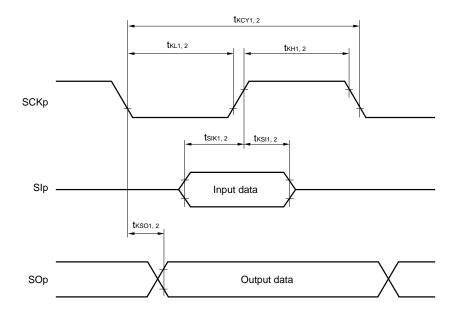
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11))

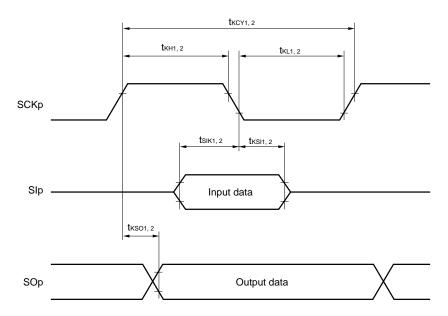
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21)

2. m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)

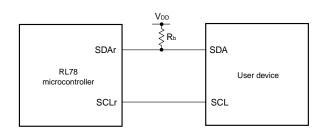
(4) During communication at same potential (simplified I^2C mode) $(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \leq EV_{DD0} \leq V_{DD} \leq 3.6 \text{ V}, \text{Vss} = EV_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
SCLr clock frequency	fscL	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$		400 ^{Note 1}	kHz
		$2.4~V \le EV_{DD0} \le 3.6~V,$ $C_b = 100~pF,~R_b = 3~k\Omega$		100 ^{Note 1}	kHz
Hold time when SCLr = "L"	tLOW	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$	1200		ns
		$2.4~V \le EV_{DD0} \le 3.6~V,$ $C_b = 100~pF,~R_b = 3~k\Omega$	4600		ns
Hold time when SCLr = "H"	thigh	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$	1200		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 3 \text{ k}Ω$	4600		ns
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$	1/f _{MCK} + 220 ^{Note 2}		ns
		$2.4~V \le EV_{DD} \le 3.6~V,$ $C_b = 100~pF,~R_b = 3~k\Omega$	1/f _{MCK} + 580 ^{Note 2}		ns
Data hold time (transmission)	thd:dat	$2.7~V \leq EV_{DD0} \leq 3.6~V,$ $C_b = 50~pF,~R_b = 2.7~k\Omega$	0	770	ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 3 \text{ k}Ω$	0	1420	ns

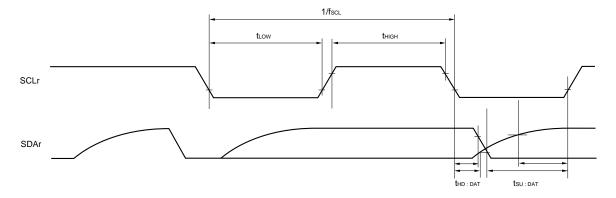
- Notes 1. The value must also be fclk/4 or lower.
 - 2. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the normal input buffer and the N-ch open drain output (Vpb tolerance (When 25- to 48-pin products)/EVpb tolerance (When 64-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).

Simplified I²C mode mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** $R_b[\Omega]$: Communication line (SDAr) pull-up resistance, $C_b[F]$: Communication line (SDAr, SCLr) load capacitance
 - 2. r: IIC number (r = 00, 01, 10, 11, 20, 21), g: PIM number (g = 0, 1), h: POM number (h = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number, mn = 00 to 03, 10, 11)

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(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2) (T_A = −40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol		Conditions				MAX.	Unit
Transfer rate ^{Note 1}		Reception	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$				fмск/12	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate fclk = 32 MHz, fMck = fclk			2.6	Mbps
			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$				fмск/12	bps
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate fclk = 32 MHz, fmck = fclk			2.6 ^{Note 2}	Mbps

- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.
 - 2. The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$.

 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 2.7 \text{ V}$: MAX. 1.3 Mbps

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VL, see the DC characteristics with TTL input buffer selected.

Remarks 1. V_b[V]: Communication line voltage

- 2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
- 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11)



(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (2/2) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol		Cond	itions	MIN.	TYP.	MAX.	Unit
Transfer		Transmission	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$				Note 1	bps
rate			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3 \text{ V}$			1.2 ^{Note 2}	Mbps
			2.4 V ≤ EV _{DD0} < 3.3 V,				Note 3	bps
			$1.6~V \le V_b \le 2.0~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$			0.43 ^{Note 4}	Mbps

Notes 1. The smaller maximum transfer rate derived by using fmck/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD0} \leq 3.6 V and 2.3 V \leq V_b \leq 2.7 V

$$\label{eq:maximum transfer rate} \begin{split} & \frac{1}{\{-C_b \times R_b \times \text{ln } (1-\frac{2.0}{V_b})\} \times 3} \end{split} \text{ [bps]}$$

$$\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \text{ln} \\ \text{Baud rate error (theoretical value)} = \frac{(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **2.** This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 1** above to calculate the maximum transfer rate under conditions of the customer.
- **3.** The smaller maximum transfer rate derived by using fmck/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.4 V \leq EV_{DD0} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

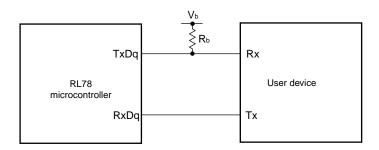
$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln{(1 - \frac{1.5}{V_b})}\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 3** above to calculate the maximum transfer rate under conditions of the customer.

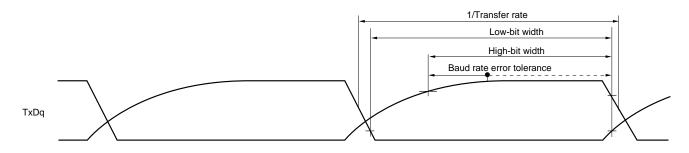
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

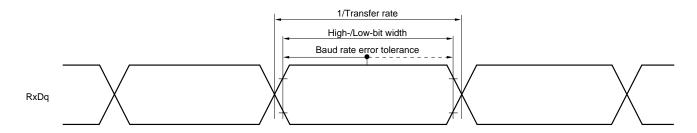


UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.** $R_b[\Omega]$: Communication line (TxDq) pull-up resistance,
 - C_b[F]: Communication line (TxDq) load capacitance, V_b[V]: Communication line voltage
 - 2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))

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(6) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (1/2) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \leq \text{EV}_{DD0} \leq \text{V}_{DD} \leq 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$\begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 30 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	tkcy1 ≥ 4/fclk	1000			ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V},$ $1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 5.5 \text{ k}\Omega$	tkcy1 ≥ 4/fclk	2300			ns
SCKp high-level width	t _{KH1}	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \\ C_b = 30 \text{ pF}, \ R_b = 2.7 \text{ k}\Omega $	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega$				ns
			$V_b \leq 2.0 \ V,$	tkcy1/2 - 916			ns
SCKp low-level width	t _{KL1}	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \\ C_b = 30 \text{ pF}, \ R_b = 2.7 \text{ k}\Omega $	$V_b \leq 2.7 \ V,$	tксү1/2 — 36			ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, 1.6 \text{ V} \le C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}Ω$	$V_b \le 2.0 V$	tkcy1/2 - 100			ns

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remarks 1. R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage

- 2. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
- **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



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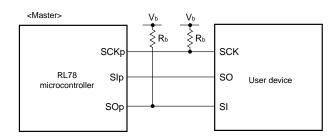
(6) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (2/2) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SIp setup time (to SCKp↑) ^{Note 1}	tsıĸ1		354			ns
			958			ns
SIp hold time (from SCKp↑) ^{Note 1}	t _{KSI1}	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	38			ns
			38			ns
Delay time from SCKp↓ to SOp output ^{Note 1}	tkso1				390	ns
					966	ns
SIp setup time (to SCKp↓) ^{Note 2}	tsıĸı	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	88			ns
			220			ns
SIp hold time (from SCKp↓) ^{Note 2}	t KSI1	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	38			ns
			38			ns
Delay time from SCKp↑ to SOp output ^{Note 2}	tkso1	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $			50	ns
					50	ns

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For Vн and V_{IL}, see the DC characteristics with TTL input buffer selected.

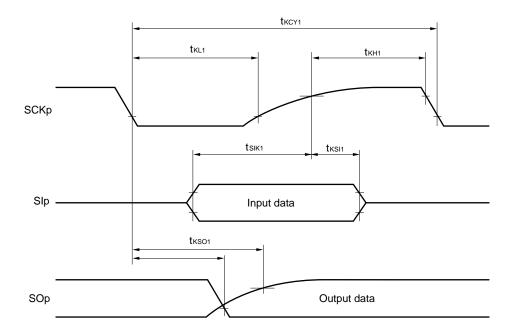
CSI mode connection diagram (during communication at different potential)



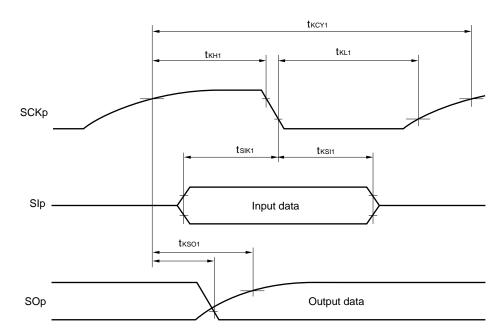
- **Remarks 1.** $R_b[\Omega]$: Communication line (SCKp, SOp) pull-up resistance, $C_b[F]$: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - 3. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

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CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (m = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(7) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (slave mode, SCKp... external clock input) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time ^{Note 1}	tkcy2	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$	24 MHz < fmck	40/fмск			ns
		$2.3~V \leq V_b \leq 2.7~V$	20 MHz < f _{MCK} ≤ 24 MHz	32/fмск			ns
			16 MHz < f _{MCK} ≤ 20 MHz	28/fмск			ns
			8 MHz < f _{MCK} ≤ 16 MHz	24/fмск			ns
			4 MHz < f _{MCK} ≤ 8 MHz	16/fмск			ns
			fмcк≤4 MHz	12/fмск			ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$	24 MHz < fмск	96/fмск			ns
		$1.6~V \le V_b \le 2.0~V$	20 MHz < f _{MCK} ≤ 24 MHz	72/f мск			ns
			16 MHz < f _{MCK} ≤ 20 MHz	64/fмск			ns
			8 MHz < f _{MCK} ≤ 16 MHz	52/f мск			ns
			4 MHz < fmck≤8 MHz	32/fмск			ns
			fмcк≤4 MHz	20/fмск			ns
SCKp high-/low-level width	t _{KH2} ,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2$	$2.3~V \leq V_b \leq 2.7~V$	tkcy2/2 - 36			ns
	t _{KL2}	2.4 V ≤ EV _{DD0} < 3.3 V, 1	$1.6 \text{ V} \le V_b \le 2.0 \text{ V}$	tkcy2/2 - 100			ns
SIp setup time	tsık2	2.7 V ≤ EV _{DD0} ≤ 3.6 V, 2	$2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V}$	1/f _{MCK} + 40			ns
(to SCKp↑) ^{Note 2}		2.4 V ≤ EV _{DD0} < 3.3 V,	$1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V}$	1/fmck + 60			
SIp hold time (from SCKp↑) ^{Note 2}	tks12			1/f _{MCK} + 62			ns
Delay time from SCKp↓ to SOp output ^{Note 3}	tkso2	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	•			2/fмск + 428	ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 5.5 \text{ k}\Omega$				2/fмск + 1146	ns

Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

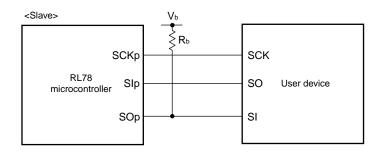
- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

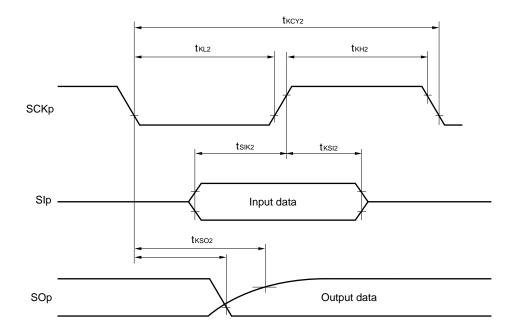


CSI mode connection diagram (during communication at different potential)

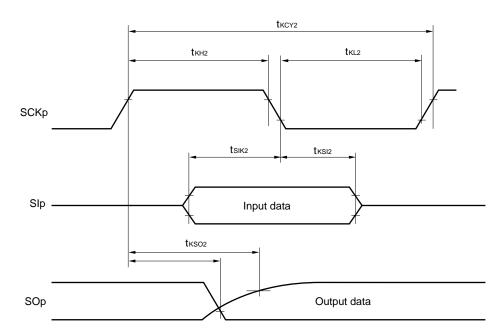


- **Remarks 1.** R_b[Ω]: Communication line (SOp) pull-up resistance, C_b[F]: Communication line (SOp) load capacitance, V_b[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10))
 - **4.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(8) Communication at different potential (1.8 V, 2.5 V) (simplified I^2C mode) (1/2) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
SCLr clock frequency	fscL	$\begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		400 ^{Note 1}	kHz
		$\begin{aligned} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{aligned}$		100 ^{Note 1}	kHz
		$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \\ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, \text{ R}_{\text{b}} = 5.5 \text{ k}\Omega$		100 ^{Note 1}	kHz
Hold time when SCLr = "L"	tLow	$\begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	1200		ns
		$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	4600		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \\ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, \text{ R}_{\text{b}} = 5.5 \text{ k}\Omega$	4650		ns
Hold time when SCLr = "H"	tнісн	$\begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	500		ns
		$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega $	2400		ns
		$2.4 \ V \leq EV_{DD0} < 3.3 \ V,$ $1.6 \ V \leq V_b \leq 2.0 \ V,$ $C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega$	1830		ns

(Notes, Caution and Remarks are listed on the next page.)

(8) Communication at different potential (1.8 V, 2.5 V) (simplified I^2C mode) (2/2) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, Vss = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
Data setup time (reception)	tsu:dat	$ 2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 50 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega $	1/f _{MCK} + 340 ^{Note 2}		ns
		$ \begin{aligned} 2.7 & \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}, \\ 2.3 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{C}_{\text{b}} &= 100 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{aligned} $	1/f _{MCK} + 760 ^{Note 2}		ns
		$ 2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \\ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 5.5 \text{ k}\Omega $	1/f _{MCK} + 570 ^{Note 2}		ns
Data hold time (transmission)	thd:dat	$\begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_{b} \leq 2.7 \ V, \\ C_{b} &= 50 \ pF, \ R_{b} = 2.7 \ k \Omega \end{split}$	0	770	ns
		$\label{eq:substitution} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_{b} \leq 2.7 \ V, \\ C_{b} &= 100 \ pF, \ R_{b} = 2.7 \ k \Omega \end{split}$	0	1420	ns
		$ \begin{aligned} 2.4 & \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \\ 1.6 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}, \\ \text{C}_{\text{b}} = 100 \text{ pF}, \text{ R}_{\text{b}} = 5.5 \text{ k}\Omega \end{aligned} $	0	1215	ns

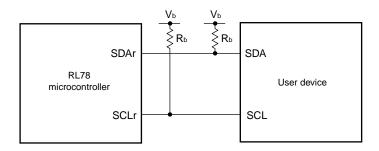
- **Notes 1.** The value must also be fclk/4 or lower.
 - 2. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".

Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

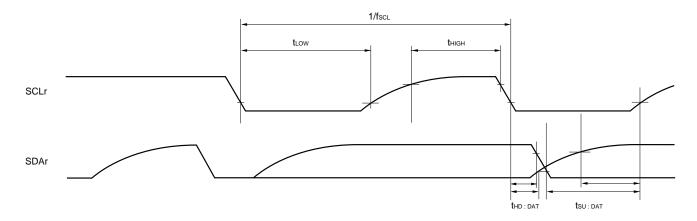
(Remarks are listed on the next page.)

<R>

Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** $R_b[\Omega]$: Communication line (SDAr, SCLr) pull-up resistance, $C_b[F]$: Communication line (SDAr, SCLr) load capacitance, $V_b[V]$: Communication line voltage
 - 2. r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
 n: Channel number (mn = 00, 02, 10)
 - **4.** IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.

3.5.2 Serial interface IICA

(1) I²C standard mode, fast mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions		Standard Mode		Fast Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode: fclk ≥ 3.5 MHz	$2.4~V \le EV_{DD0} \le 3.6~V$			0	400	kHz
		Normal mode: fcLK ≥ 1 MHz	$2.4~V \le EV_{DD0} \le 3.6~V$	0	100			kHz
Setup time of restart condition	tsu:sta			4.7		0.6		μs
Hold time ^{Note 1}	thd:STA			4.0		0.6		μs
Hold time when SCLA0 = "L"	tLOW			4.7		1.3		μs
Hold time when SCLA0 = "H"	t HIGH			4.0		0.6		μs
Data setup time (reception)	tsu:dat			250		100		ns
Data hold time (transmission)Note 2	thd:dat			0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto			4.0		0.6		μs
Bus-free time	t BUF			4.7		1.3		μs

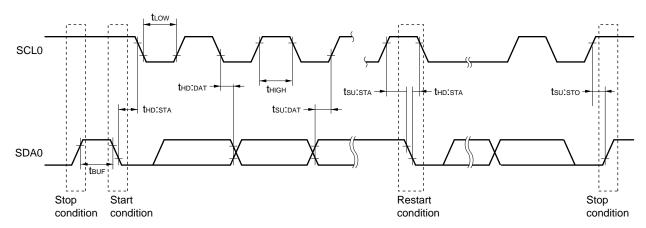
Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of thd:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 k Ω Fast mode: C_b = 320 pF, R_b = 1.1 k Ω

IICA serial transfer timing



3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Division of A/D Converter Characteristics

Reference voltag	Reference voltage (+) = AV _{REFP} Reference voltage (-) = AV _{REFM}	Reference voltage (+) = AV _{DD} Reference voltage (-) = AV _{SS}	Reference voltage (+) = Internal refrence voltage Reference voltage (-) = AVss
High-accuracy channel; ANI0 to ANI12 (input buffer power supply: AV _{DD})	See 3.6.1 (1)	See 3.6.1 (2)	See 3.6.1 (5)
Standard channel; ANI16 to ANI30 (input buffer power supply: V _{DD} or EV _{DD0})	See 3.6.1 (3)	See 3.6.1 (4)	
Temperature sensor, internal reference voltage output	See 3.6.1 (3)	See 3.6.1 (4)	-

<R> (1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

(TA = -40 to +105°C, 2.4 V \leq AVREFP \leq AVDD \leq VDD \leq 3.6 V, Vss = 0 V, AVss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol		Conditions			MAX.	Unit
Resolution	Res		$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8.		12.	bit
Overall error ^{Note}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±6.0	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	3.375			μs
Zero-scale error ^{Note}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
Full-scale error ^{Note}	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
Integral linearity error ^{Note}	ILE	12-bit resolution	2.4 V ≤ AVREFP ≤ AVDD ≤ 3.6 V			±2.0	LSB
Differential linearity error ^{Note}	DLE	12-bit resolution	$2.4~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±1.5	LSB
Analog input voltage	Vain			0		AVREFP	٧

Note Excludes quantization error (±1/2 LSB).

<R> (2) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI0 to ANI12

(TA = -40 to +105°C, 2.4 V \leq AVDD \leq VDD \leq 3.6 V, Vss = 0 V, AVss = 0 V, Reference voltage (+) = AVDD, Reference voltage (-) = AVss = 0 V)

Parameter	Symbol	(MIN.	TYP.	MAX.	Unit	
Resolution	Res		2.4 V ≤ AV _{DD} ≤ 3.6 V	8		12	bit
Overall error ^{Note}	AINL	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±7.5	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4~V \le AV_{DD} \le 3.6~V$	3.375			μs
Zero-scale error ^{Note}	Ezs	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±6.0	LSB
Full-scale error ^{Note}	Ers	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±6.0	LSB
Integral linearity error ^{Note}	ILE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±3.0	LSB
Differential linearity error Note	DLE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.0	LSB
Analog input voltage	Vain	_		0		AV _{DD}	V

Note Excludes quantization error (±1/2 LSB).

<R> (3) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

(TA = -40 to +105°C, 2.4 V \leq EVDD0 \leq VDD \leq 3.6 V, 2.4 V \leq AVREFP \leq AVDD \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V, AVss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		2.4 V ≤ AV _{REFP} ≤ AV _{DD} ≤ 3.6 V	8		12	bit
Overall error ^{Note 1}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±7.0	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	4.125			μs
Zero-scale error ^{Note 1}	Ezs	12-bit resolution	2.4 V ≤ AV _{REFP} ≤ AV _{DD} ≤ 3.6 V			±5.0	LSB
Full-scale errorNote 1	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±5.0	LSB
Integral linearity error ^{Note 1}	ILE	12-bit resolution	2.4 V ≤ AV _{REFP} ≤ AV _{DD} ≤ 3.6 V			±3.0	LSB
Differential linearity errorNote 1	DLE	12-bit resolution	$2.4~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±2.0	LSB
Analog input voltage	Vain			0.		AV _{REFP} and EV _{DD0}	V
		Interanal reference (2.4 V ≤ V _{DD} ≤ 3.6 \		VBGR ^{Note 2}		V	
		•	Temperature sensor output voltage (2.4 V \leq V _{DD} \leq 3.6 V, HS (high-speed main) mode)			2	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

2. See 3.6.2 Temperature sensor, internal reference voltage output characteristics.

<R> (4) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}0} \le \text{V}_{\text{DD}0} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS}0} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+) = AV}_{\text{DD}}, \text{Reference voltage (-) = AV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	С	conditions	MIN.	TYP.	MAX.	Unit	
Resolution	Res		2.4 V ≤ AV _{DD} ≤ 3.6 V	8		12	bit	
Overall error ^{Note 1}	AINL	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±8.5	LSB	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	4.125			μs	
Zero-scale error ^{Note 1}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±8.0	LSB	
Full-scale error ^{Note 1}	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±8.0	LSB	
Integral linearity errorNote 1	ILE	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±3.5	LSB	
Differential linearity errorNote 1	DLE	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±2.5	LSB	
Analog input voltage	Vain			0		AV _{DD} and EV _{DD0}	V	
		Interanal reference vol (2.4 V ≤ V _{DD} ≤ 3.6 V, H	V _{BGR} Note 2			V		
		•	Temperature sensor output voltage (2.4 V \leq V _{DD} \leq 3.6 V, HS (high-speed main) mode)			V _{TMPS25} Note 2		

- Notes 1. Excludes quantization error (±1/2 LSB).
 - 2. See 3.6.2 Temperature sensor, internal reference voltage output characteristics.

<R> (5) When reference voltage (+) = Internal reference voltage (1.45 V) (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVss (ADREFM = 0), target for conversion: ANI0 to ANI12, ANI16 to ANI30

(TA = -40 to +105°C, 2.4 V \leq VDD \leq 3.6 V, 2.4 V \leq EVDD \leq VDD, 2.4 V \leq AVDD \leq VDD, VSS = EVSS0 = 0 V, AVSS = 0 V, Reference voltage (+) = Internal reference voltage, Reference voltage (-) = AVSS = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions		TYP.	MAX.	Unit
Resolution	Res			8		
Conversion time	tconv	8-bit resolution	16.0			μs
Zero-scale error ^{Note}	Ezs	8-bit resolution			±4.0	LSB
Integral linearity error ^{Note}	ILE	8-bit resolution			±2.0	LSB
Differential linearity error ^{Note}	DLE	8-bit resolution			±2.5	LSB
Reference voltage (+)	AV _{REF(+)}	= Internal reference voltage (V _{BGR})	1.38	1.45	1.50	V
Analog input voltage	VAIN		0		V _{BGR}	٧

Note Excludes quantization error (±1/2 LSB).

3.6.2 Temperature sensor, internal reference voltage output characteristics

(T_A = -40 to +105°C, 2.4 V \leq V_{DD} \leq 3.6 V, V_{SS} = 0 V, HS (high-speed main) mode)

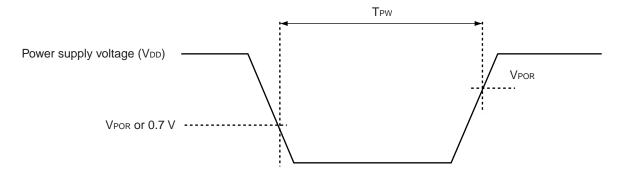
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V _{TMPS25}	Setting ADS register = 80H, T _A = +25°C		1.05		V
Internal reference voltage	V _{BGR}	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		10			μs

3.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V _{POR}	Power supply rise time		1.51	1.57	٧
	V _{PDR}	Power supply fall time	1.44	1.50	1.56	٧
Minimum pulse width ^{Note}	T _{PW}		300			μs

Note This is the time required for the POR circuit to execute a reset when V_{DD} falls below V_{PDR}. When the microcontroller enters STOP mode or if the main system clock (f_{MAIN}) has been stopped by setting bit 0 (HIOSTOP) and bit 7 (MSTOP) of the clock operation status control register (CSC), this is the time required for the POR circuit to execute a reset before V_{DD} rises to V_{POR} after having fallen below 0.7 V.



3.6.4 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	V _{LVD2}	Power supply rise time	3.01	3.13	3.25	V
voltage			Power supply fall time	2.94	3.06	3.18	V
		V _{LVD3}	Power supply rise time	2.90	3.02	3.14	V
			Power supply fall time	2.85	2.96	3.07	V
		V _{LVD4}	Power supply rise time	2.81	2.92	3.03	V
			Power supply fall time	2.75	2.86	2.97	V
		V _{LVD5}	Power supply rise time	2.70	2.81	2.92	V
			Power supply fall time	2.64	2.75	2.86	V
		V _{LVD6}	Power supply rise time	2.61	2.71	2.81	V
			Power supply fall time	2.55	2.65	2.75	V
		V _{LVD7}	Power supply rise time	2.51	2.61	2.71	V
			Power supply fall time	2.45	2.55	2.65	V
Minimum pu	lse width	t _{LW}		300			μs
Detection de	elay time					300	μs

Remark $V_{LVD(n-1)} > V_{LVDn}$: n = 3 to 7

LVD Detection Voltage of Interrupt & Reset Mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol		Conc	litions	MIN.	TYP.	MAX.	Unit
Interrupt & reset	V _{LVD5}	VPOC	2, VPOC1, VPOC0 = 0), 1, 1, falling reset voltage	2.64	2.75	2.86	V
mode	V _{LVD4}		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	V
	V _{LVD3}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: V_{DD} = 2.7 to 3.6 V@1 MHz to 32 MHz

V_{DD} = 2.4 to 3.6 V@1 MHz to 16 MHz

3.6.5 Supply voltage rise slope characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SV _{DD}				54	V/ms

Caution Be sure to maintain the internal reset state until VDD reaches the operating voltage range specified in 3.4 AC Characteristics, by using the LVD circuit or external reset pin.

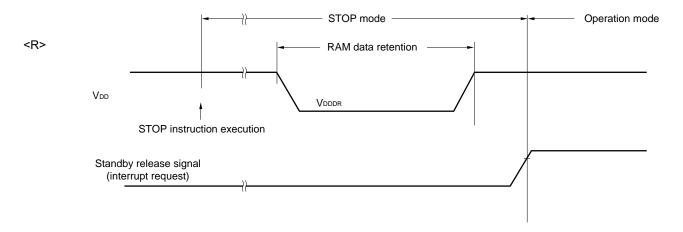


<R> 3.7 RAM Data Retention Characteristics

$< R > (T_A = -40 \text{ to } +105^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 ^{Note}		3.6	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



3.8 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclk	$2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}$	1		32	MHz
Number of code flash rewrites ^{Notes 1, 2, 3}	Cerwr	Retained for 20 years TA = 85°C	1,000			Times
Number of data flash rewrites ^{Notes 1, 2, 3}		Retained for 1 years TA = 25°C		1,000,000		
		Retained for 5 years TA = 85°C	100,000			
		Retained for 20 years TA = 85°C	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

2. When using flash memory programmer and Renesas Electronics self programming library

- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
- 4. This temperature is the average value at which data are retained.

<R>

Dedicated Flash Memory Programmer Communication (UART) 3.9

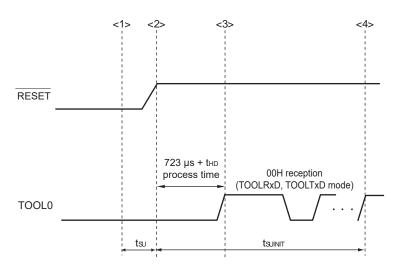
$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115.2 k		1 M	bps

Timing Specs for Switching Flash Memory Programming Modes 3.10

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
	How long from when an external reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the external reset ends.			100	ms
	How long from when the TOOL0 pin is placed at the low level until a external reset ends	tsu	POR and LVD reset must end before the external reset ends.	10			μs
<r></r>	How long the TOOL0 pin must be kept at the low level after an external reset ends (except flash firmware processing time)	t HD	POR and LVD reset must end before the external reset ends.	1			ms



<R>

<R>

- <1> The low level is input to the TOOL0 pin.
- <2> The pins reset ends (POR and LVD reset must end before the external reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

tsu: How long from when the TOOL0 pin is placed at the low level until a external reset ends

How long to keep the TOOL0 pin at the low level from when the external resets end (except flash tHD: firmware processing time)

4. PACKAGE DRAWINGS

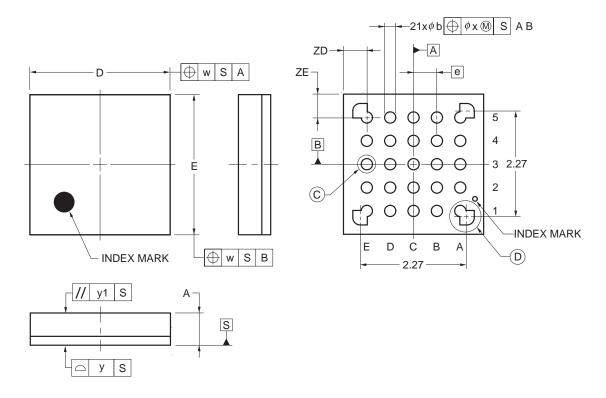
4.1 25-pin products

R5F10E8AALA, R5F10E8CALA, R5F10E8DALA, R5F10E8EALA

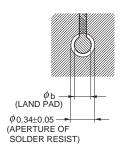
<	R>
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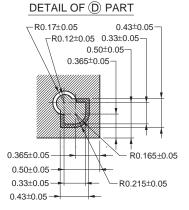
JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-WFLGA25-3x3-0.50	PWLG0025KA-A	P25FC-50-2N2-3	0.01

Unit: mm









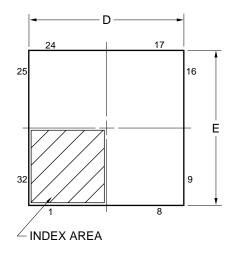
ITEM	DIMENSIONS			
D	3.00±0.10			
Е	3.00±0.10			
W	0.20			
е	0.50			
Α	0.69±0.07			
b	0.24±0.05			
х	0.05			
у	0.08			
у1	0.20			
ZD	0.50			
ZE	0.50			

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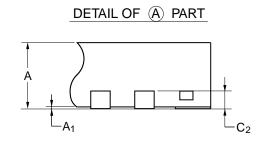
4.2 32-pin products

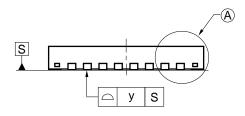
R5F10EBAANA, R5F10EBCANA, R5F10EBDANA, R5F10EBEANA R5F10EBAGNA, R5F10EBCGNA, R5F10EBCGNA, R5F10EBCGNA

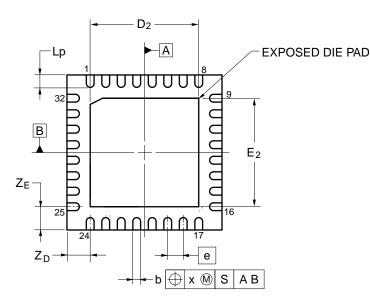
JEITA Package code	RENESAS code	Previous code	MASS(TYP.)[g]
P-HWQFN32-5x5-0.50	PWQN0032KB-A	P32K8-50-3B4-5	0.06











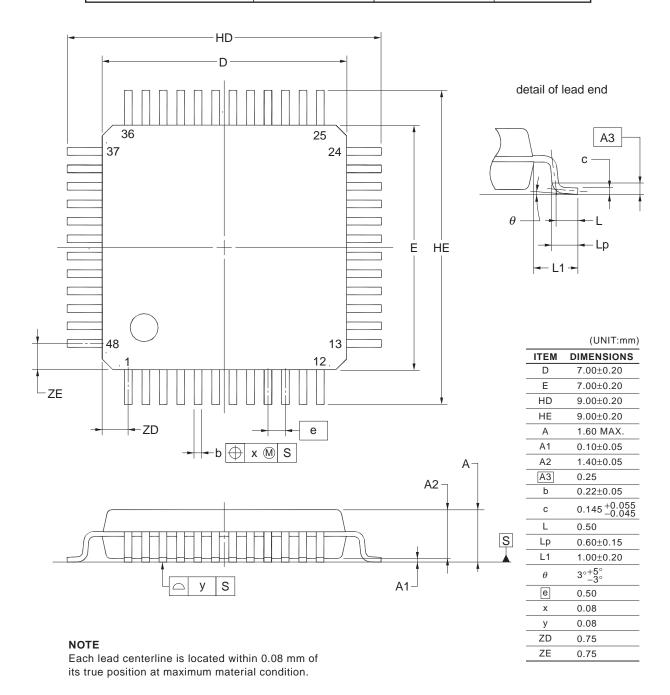
Referance	Dimens	sion in Mil	limeters
Symbol	Min	Nom	Max
D	4.95	5.00	5.05
Е	4.95	5.00	5.05
А			0.80
A ₁	0.00		
b	0.18	0.25	0.30
е		0.50	
Lp	0.30	0.40	0.50
х			0.05
у			0.05
Z_D		0.75	
Z _E		0.75	
c ₂	0.15	0.20	0.25
D ₂		3.50	
E ₂		3.50	

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4.3 48-pin products

R5F10EGAAFB, R5F10EGCAFB, R5F10EGDAFB, R5F10EGEAFB R5F10EGAGFB, R5F10EGCGFB, R5F10EGCGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP48-7x7-0.50	PLQP0048KF-A	P48GA-50-8EU-1	0.16



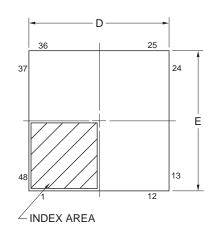
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R5F10EGAANA, R5F10EGCANA, R5F10EGDANA, R5F10EGEANA R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA

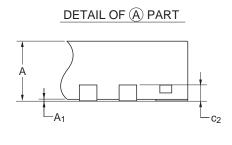
<R>

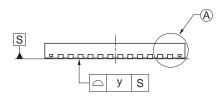
JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-HWQFN48-7x7-0.50	PWQN0048KB-A	48PJN-A P48K8-50-5B4-7	0.13

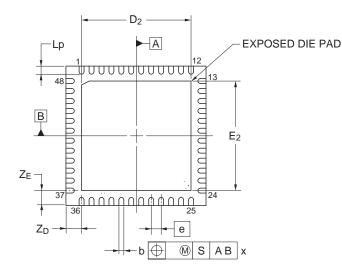
Unit: mm











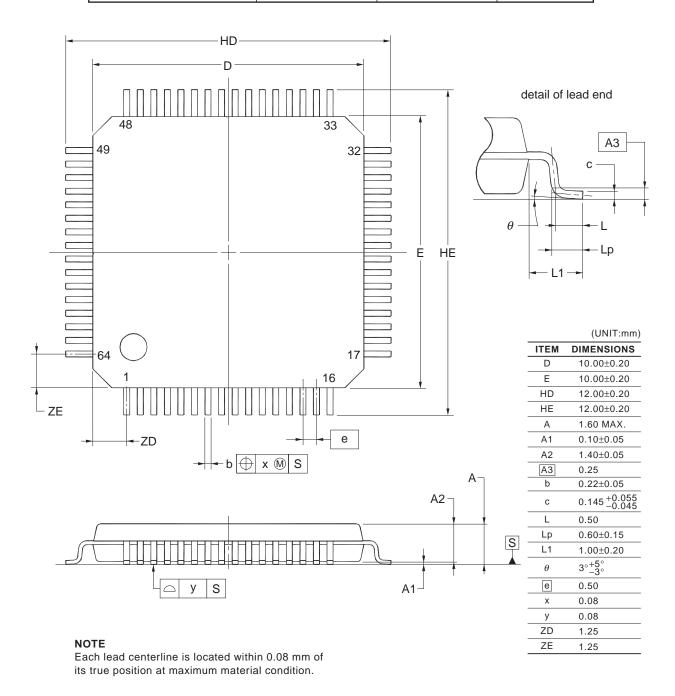
Reference Symbol	Dimensions in millimeters		
	Min	Nom	Max
D	6.95	7.00	7.05
E	6.95	7.00	7.05
Α	_	_	0.80
A ₁	0.00	_	_
b	0.18	0.25	0.30
е	_	0.50	_
Lp	0.30	0.40	0.50
х	_	_	0.05
У	_	_	0.05
Z_{D}	_	0.75	_
ZE	-	0.75	_
C ₂	0.15	0.20	0.25
D ₂	_	5.50	
E ₂		5.50	_

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4.4 64-pin products

R5F10ELCAFB, R5F10ELDAFB, R5F10ELEAFB R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB

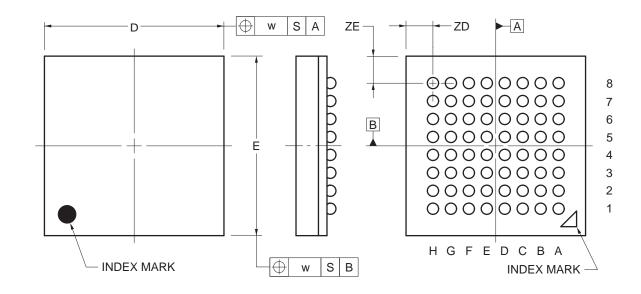
JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP64-10x10-0.50	PLQP0064KF-A	P64GB-50-UEU-2	0.35

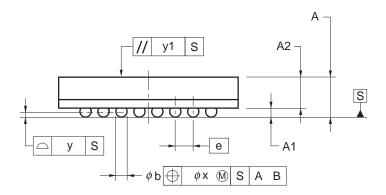


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R5F10ELCABG, R5F10ELDABG, R5F10ELEABG

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-VFBGA64-4x4-0.40	PVBG0064LA-A	P64F1-40-AA2-2	0.03





	(UNIT:mm)	
ITEM	DIMENSIONS	
D	4.00±0.10	
Е	4.00±0.10	
W	0.15	
Α	0.89±0.10	
A1	0.20±0.05	
A2	0.69	
е	0.40	
b	$0.25 {\pm} 0.05$	
х	0.05	
У	0.08	
y1	0.20	
ZD	0.60	
ZE	0.60	

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RL78/G1A Data Sheet

		Description		
Rev.	Date	Page	Summary	
0.01	Dec 26, 2011	-	First Edition issued	
1.00	Sep 25, 2013	p.1	Modification of 1.1 Features	
		p.4	Modification of Table 1-1. List of Ordering Part Numbers	
		p.6	Modification of Remark 3 to 1.3.2 32-pin products.	
		p.13	Modification of 1.5.2 32-pin products.	
		p.14	Modification of 1.5.3 48-pin products.	
		p.16	Modification of 1.6 Outline of Functions	
		p.21	Modification of 2.2.1 X1, XT1 oscillator characteristics	
		p.31, 32	Modification of Note 1 in 2.3.2 Supply current characteristics	
		p.34, 35	Modification of Minimum Instruction Execution Time during Main System Clock Operation	
		p.37	Modification of AC Timing Test Points in 2.5 Peripheral Functions Characteristics	
		p.46 to 58	Modification of Caution to 2.5.1 Serial array unit.	
		p.63 to 68	Modification of 2.6.1 A/D converter characteristics	
		p.71	Modification of 2.7 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics	
		p.71	Modification of 2.8 Flash Memory Programming Characteristics	
		p.72	Modification of 2.10 Timing Specs for Switching Flash Memory Programming Modes	
		p.73 to	Addition of 3 ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL	
		117	APPLICATIONS TA = -40 to +105°C)	
		p.118 to 123	Modification of 4. PACKAGE DRAWINGS	
2.10	Nov 30, 2016	p.4	Modification of Table 1-1. List of Ordering Part Numbers	
		p.5 to 10	Modification of the position of the index mark in 1.3.1 25-pin products to 1.3.4 64-pin products	
		p.6	Modification of Remark 3	
		p.13	Modification of 1.5.2 32-pin products	
		p.14	Modification of 1.5.3 48-pin products	
		p.16	Modification of description in 1.6 Outline of Functions	
		p.21	Modification of 2.2.1 X1, XT1 oscillator characteristics	
		p.31, 32	Modification of Note 1 in 2.3.2 Supply current characteristics	
		p.34, 35	Modification of Minimum Instruction Execution Time during Main System Clock Operation	
		p.36	Modification of AC Timing Test Points and TI/TO Timing	
		p.38	Modification of AC Timing Test Points in 2.5 Peripheral Functions Characteristics	
		p.48, 50 to 52, 55, 59	Modification of Caution in 2.5.1 Serial array unit	
		p.64 to 69	Modification of conditions of 2.6.1 A/D converter characteristics	
		p.72	Renamed to 2.7 RAM Data Retention Characteristics, and modification of note and figure	
		p.72	Modification of 2.8 Flash Memory Programming Characteristics	

			Description	
Rev.	Date	Page	Summary	
2.10	2.10 Nov 30, 2016	p.73	Modification of 2.10 Timing Specs for Switching Flash Memory Programming Modes	
		p.77	Modification of 3.2.1 X1, XT1 oscillator characteristics	
		p.78, 79	Modification of 3.3.1 Pin characteristics	
		p.88	Modification of 3.3.2 Supply current characteristics	
		p.90	Modification of Minimum Instruction Execution Time during Main System Clock Operation	
		p.91	Modification of AC Timing Test Points and TI/TO Timing	
		p.93	Modification of AC Timing Test Points in 3.5 Peripheral Functions Characteristics	
		p.95	Modification of 3.5.1 Serial array unit	
		p.99,	Modification of Caution in 2.5.1 Serial array unit	
		100,		
		102,		
		103,		
		105, 109		
		p.112 to 116	Modification of 3.6.1 (1) to (5)	
		p.118	Renamed to 3.7 RAM Data Retention Characteristics, and modification of note and figure	
		p.118	Addition of note 4 to 3.8 Flash Memory Programming Characteristics	
		p.119	Modification of 3.10 Timing Specs for Switching Flash Memory Programming Modes	
		p.120	Modification of 4.1 25-pin products	
		p.123	Modification of 4.3 48-pin products	

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NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE: Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

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